

Ionotronics

Francesco Chiabrera

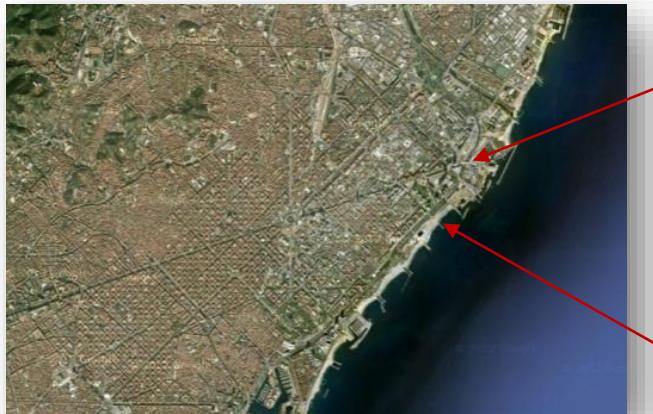
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SSI 2024, Tutorials

Catalonia Institute for Energy Research (IREC)



We are
here

This is
the
beach

Nanoionics and Fuel Cell group

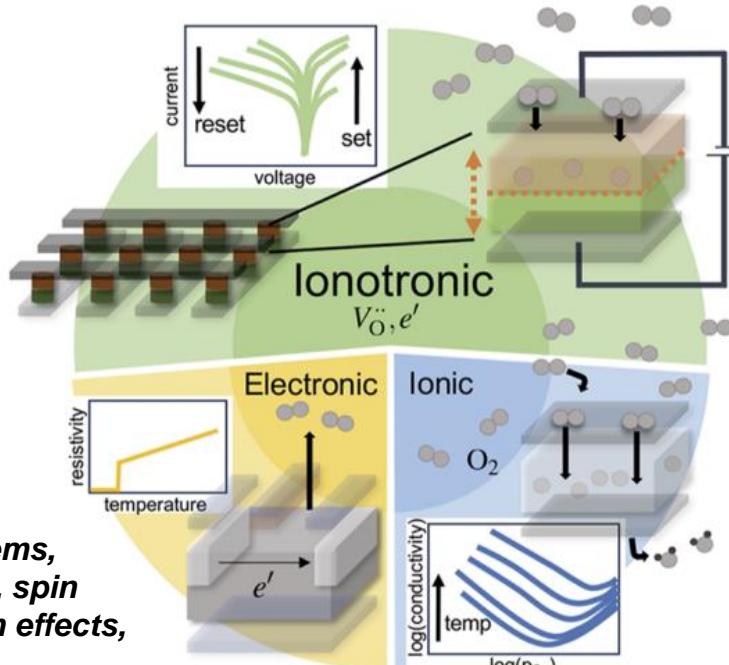


What is ionotronic?

*Memristors, Electrochemical ion synapsis,
electrochromic windows, magnetoionics, optoionics*

**Control of device
functionalities through
the accumulation/
insertion/ variation of
ion concentration**

**Correlated systems,
Superconductors, spin
modulation, quantum effects,
transistors,...**



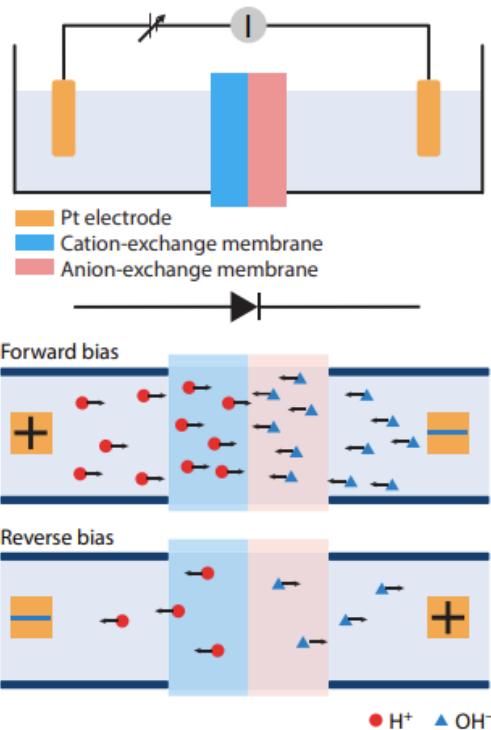
**Ionotronic phenomena in
transition metal oxides**

**Ionic conductors,
Fuel cells,
Sensors,**

Wenderott et al., APL Mater. 12, 050901 (2024)

However, Iontronics is also

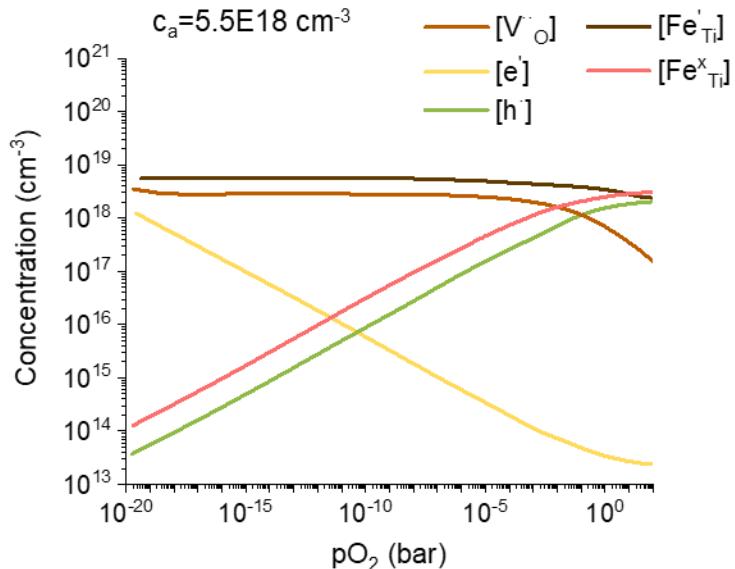
Ions as signal carriers



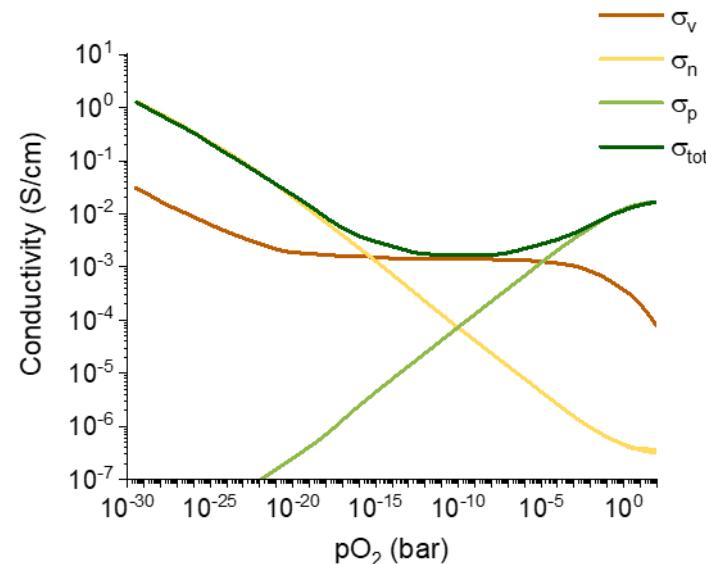
Chun et al., Annu. Rev. Anal. Chem. 2015. 8:441–62

Metal transition oxides: defect concentration and conductivity

Brouwer diagram: SrTiO_3 at 900°C



Conductivity variation

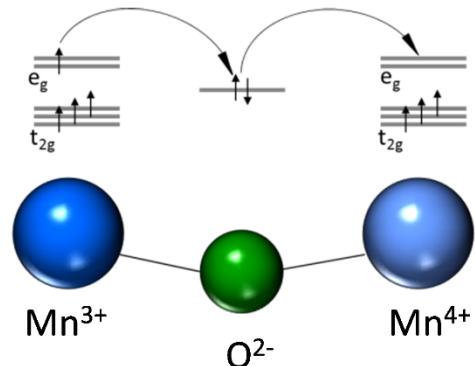


And also magnetic, optical, dielectric,...

Complex oxides: a very rich playground! Examples: $\text{La}_{1-x}\text{Sr}_x\text{MnO}_3$

Electronic transport

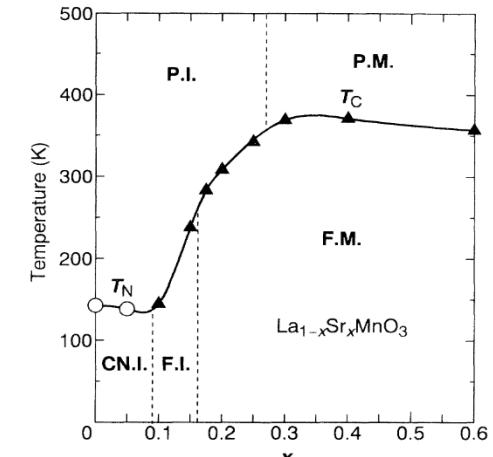
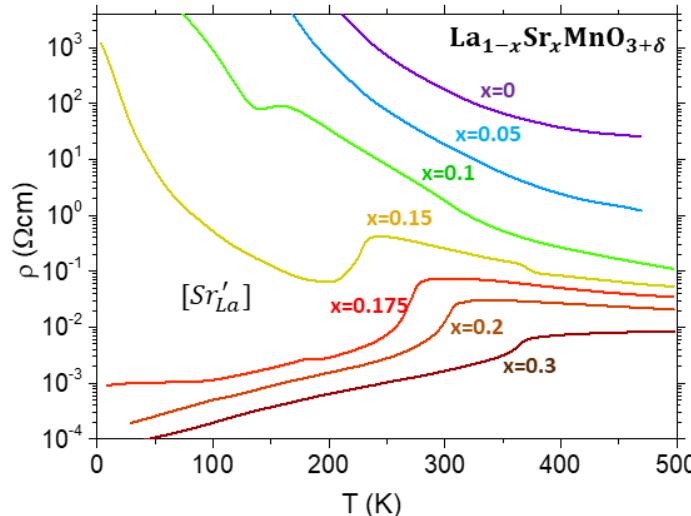
$$[\text{Sr}'_{\text{La}}] = [h^{\bullet}]$$



Above T_c: holes localized by electron-phonon coupling phenomena

Below T_c: alignment spins permits double exchange and metallic behavior

Electronic and magnetic properties

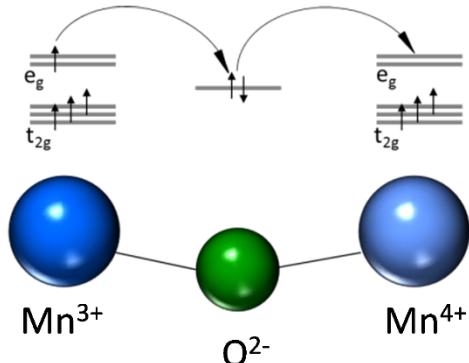


Urushibara, A. et al., *Phys. Rev. B* **51**, 103–109 (1995).

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Electronic transport

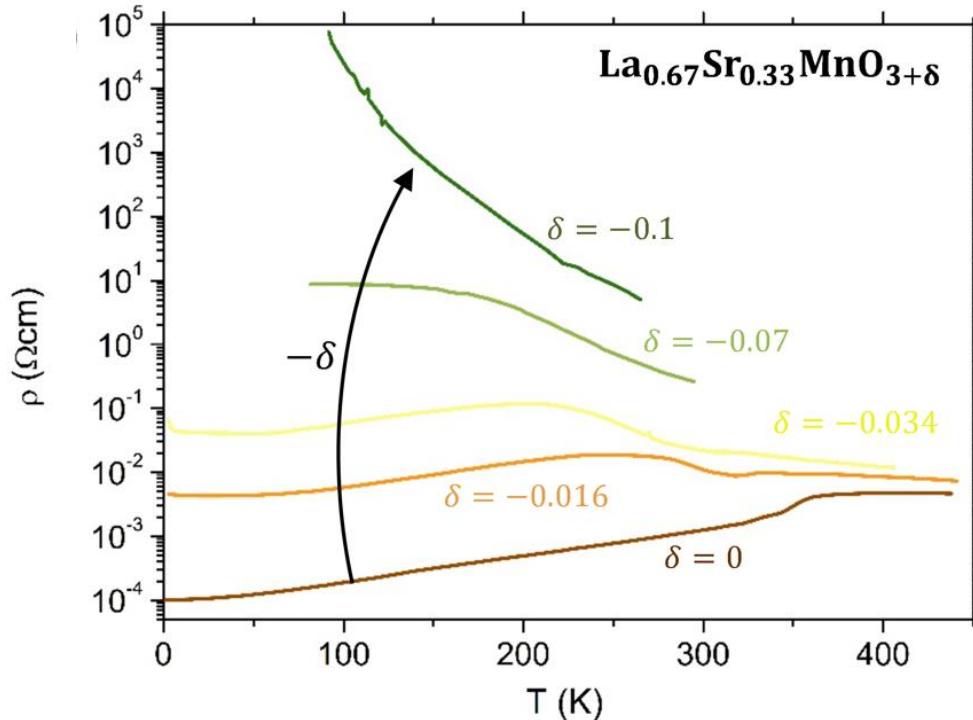
$$[\text{Sr}'_{\text{La}}] = [h^\bullet] + 2[v_0^{\bullet\bullet}]$$



Above T_c : holes localized by electron-phonon coupling phenomena

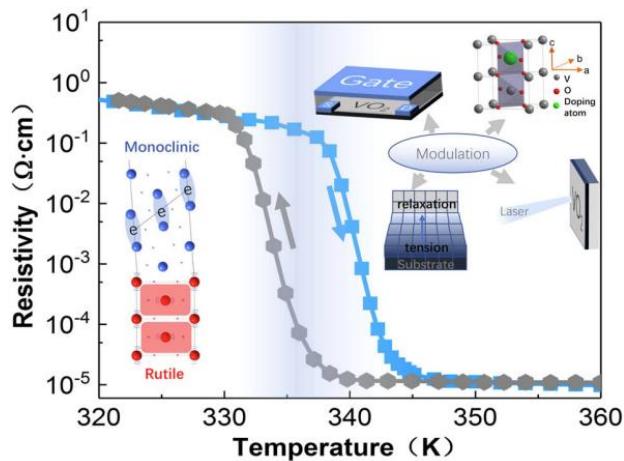
Below T_c : alignment spins permits double exchange and metallic behavior

Effect of oxygen vacancies on MI transition

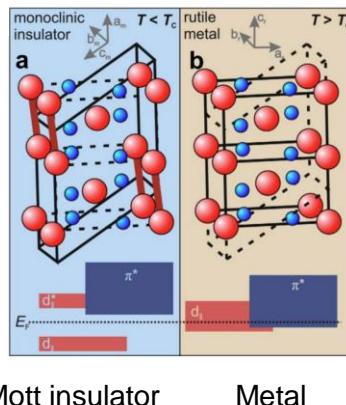


Complex oxides: a very rich playground! Examples: VO_2

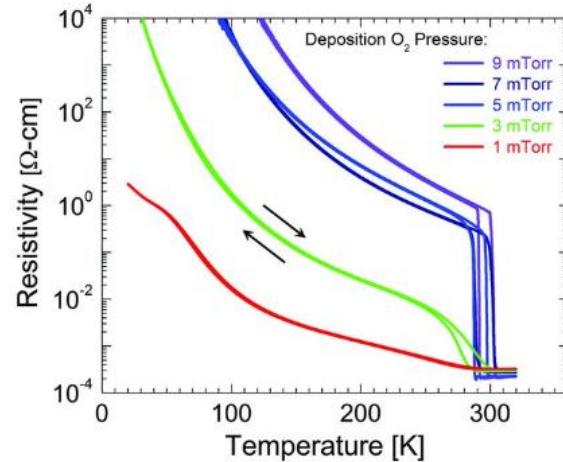
Metal insulator transition



Phase change



Oxygen vacancy modulation



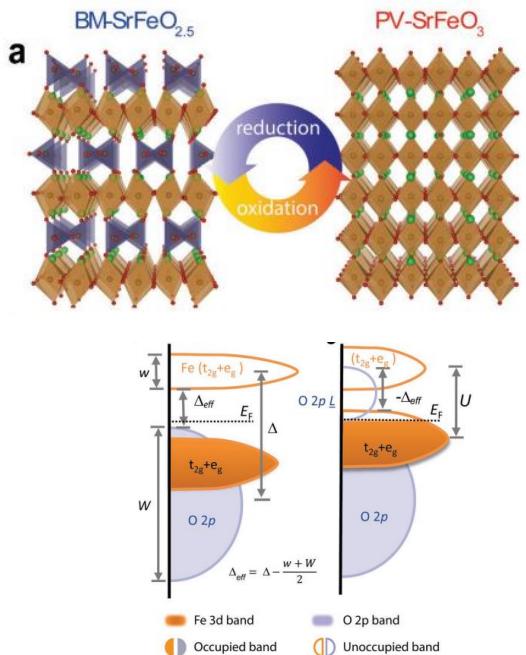
Shao et al. NPG Asia Materials (2018) 10: 581-605

Wegkamp, D. & Stähler, J, Prog. Surf. Sci. (2015) 90, 464–502

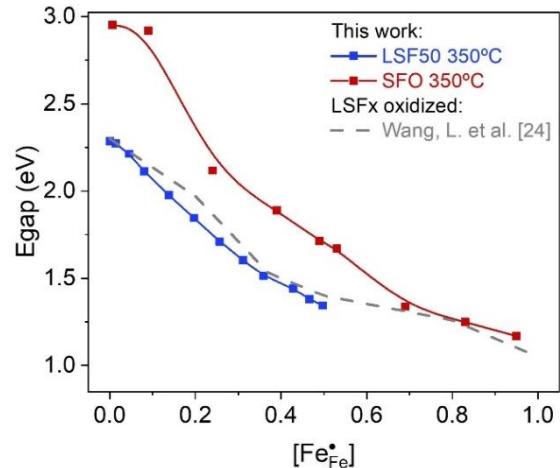
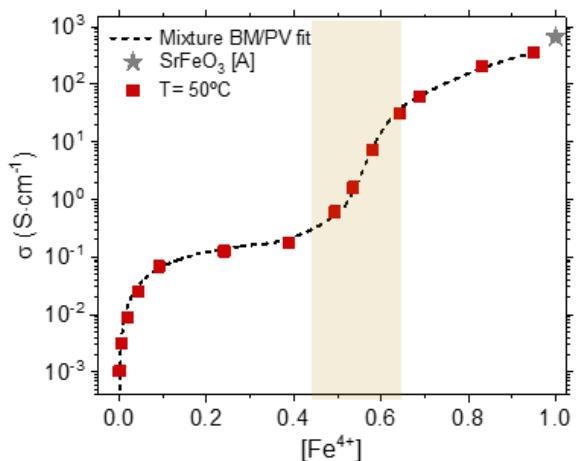
Jaewoo Jeong et al., Science, 339, 1402-1405(2013)

Complex oxides: a very rich playground! Examples: SrFeO_{3-δ}

Topotactic transition



Large conductivity and optical modulation



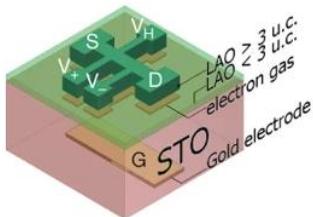
Nizet et al., submitted

Nallagatla et al., Adv. Mater. 2019, 31, 1903391

How to modulate the ionic concentration of complex oxides?

Field effect

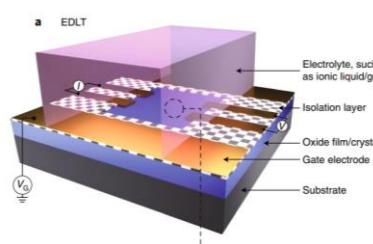
Application of E in the linear range through a dielectric



Caviglia et al, Nature (2008)
456, 624–627

Electrolyte double layer

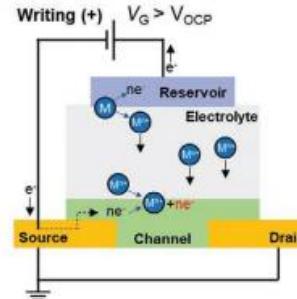
Application of E in the linear range through an ionic conductor



Leighton et al., Nat. Mat.,
(2019), 18, 13-18

Redox ionic insertion

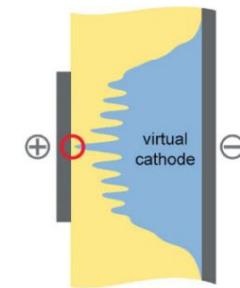
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Huang et al., Adv. Mater.
2023, 35, 2205169

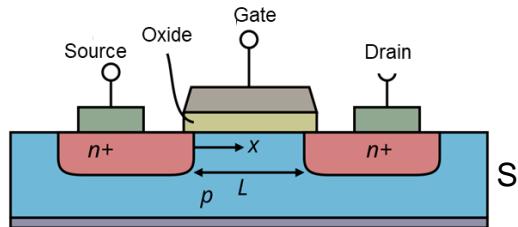
Resistive switching

Application of large E directly to the material



Waser el al., Adv. Mater.
2009, 21, 2632–2663

Metal-Oxide-Semiconductor Field-Effect Transistor (MOSFET)



$$C = \epsilon_0 \epsilon_R / d \text{ (F/cm}^2\text{)}$$

$$10 \text{ nm}, C \sim 0.3 \mu\text{F/cm}^2$$

$$Q_c = C \cdot V \sim 0.3 \mu\text{C/cm}^2$$

Poisson equation

$$\nabla^2 \varphi = -\frac{\rho}{\epsilon_0 \epsilon_R}$$

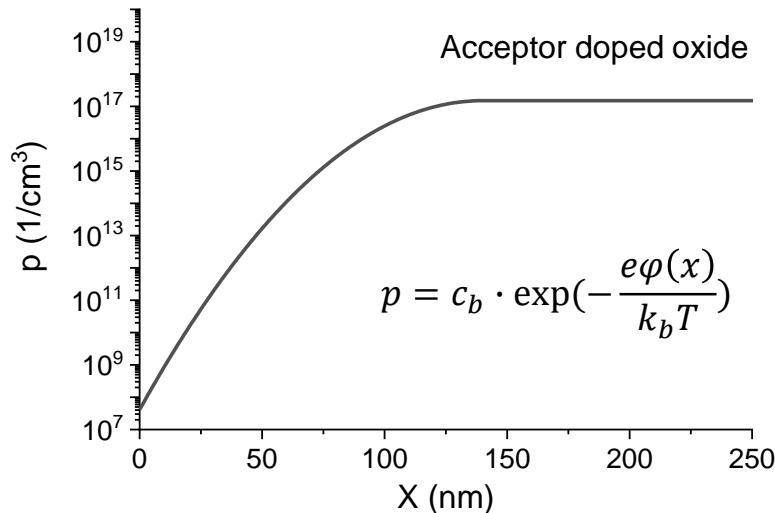
Space charge (sum of all charge and mobile defects)

Depletion approx. 1D

$$\rho = c_b$$

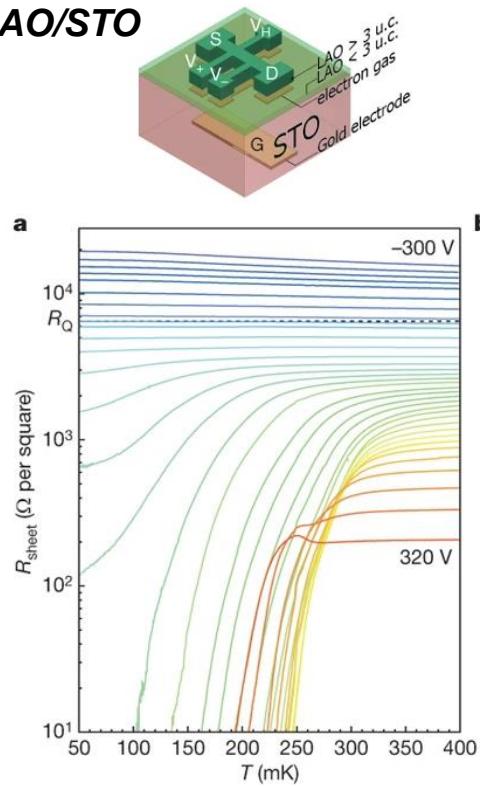
$$\varphi(x) = \varphi_0 \left(\frac{x}{\lambda} - 1 \right)^2 \text{ for } x < \lambda, \lambda = \left(\frac{2\epsilon_0 \epsilon_R \varphi_0}{e c_b} \right)^{\frac{1}{2}}$$

$$Q_c = (2\epsilon_0 \epsilon_R e \varphi_0)^{\frac{1}{2}}$$



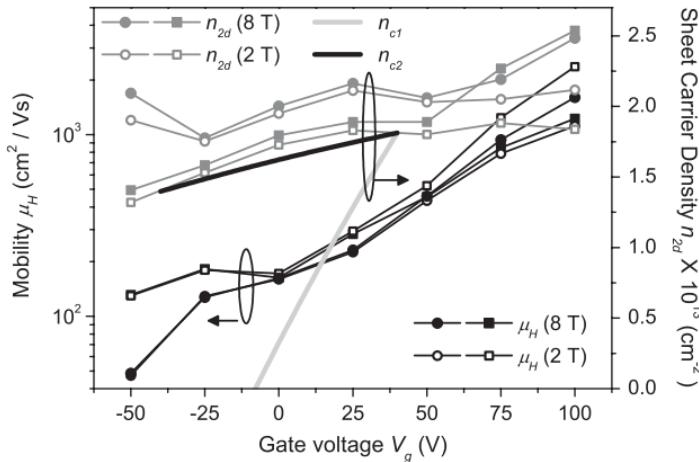
Electric field effect modulation of superconductivity in LAO/STO

LAO/STO



Caviglia et al, Nature (2008) 456, pages 624–627

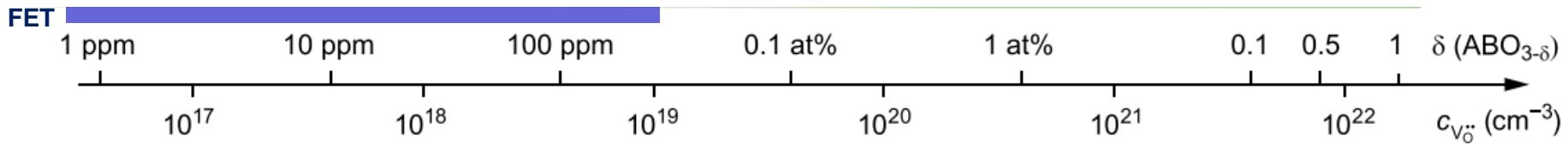
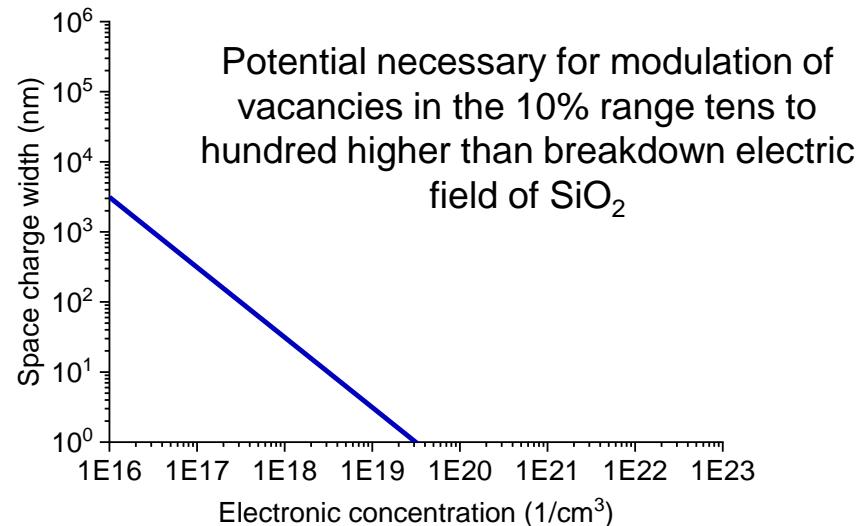
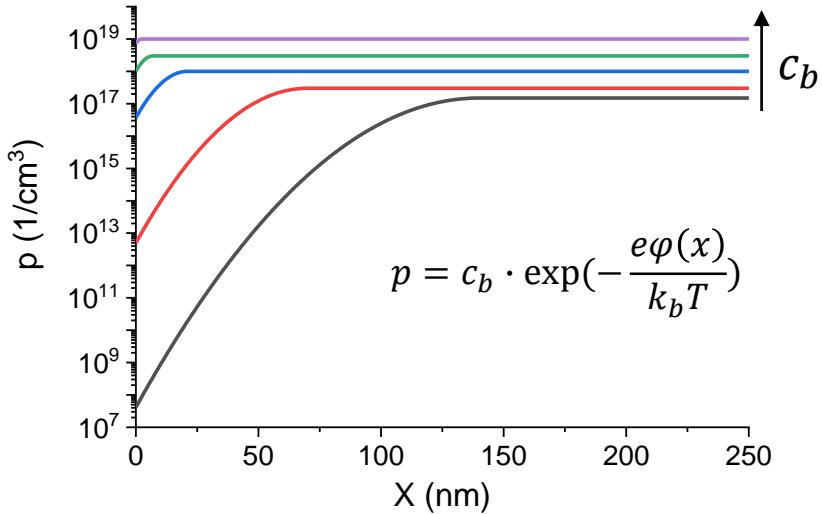
Mobility modulation rather than carrier



Bell et al., PRL 103, 226802 (2009)

- STO thick and large potentials
- Large dielectric constant at low T
- Very low defect concentration necessary

Problem! FET effect non large for high dopant concentration

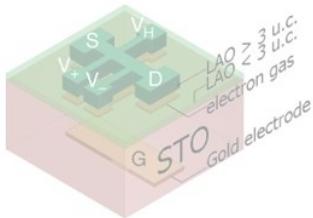


F. Gunkel et al., Appl. Phys. Lett. 116, 120505 (2020)

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Field effect

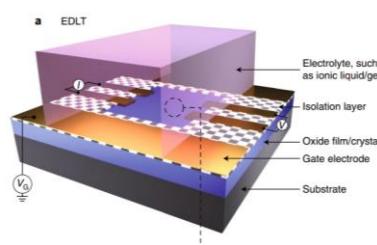
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Electrolyte double layer

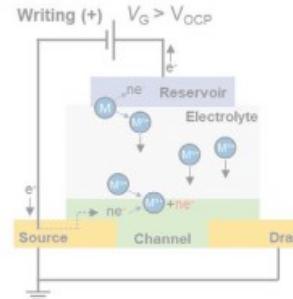
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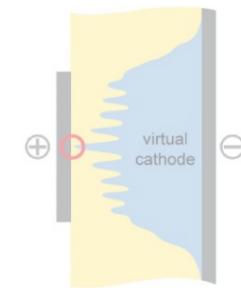
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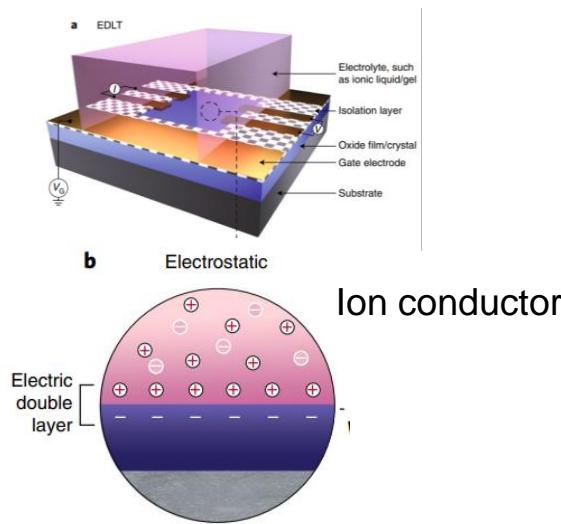
Resistive switching

Application of large E directly to the material

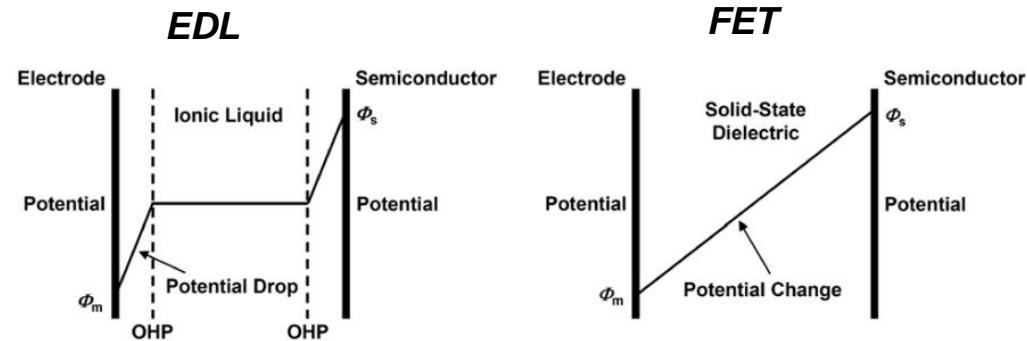


Waser et al., Adv. Mater.
2009, 21, 2632–2663

Electrolyte double layer (EDL) in ionic conductors



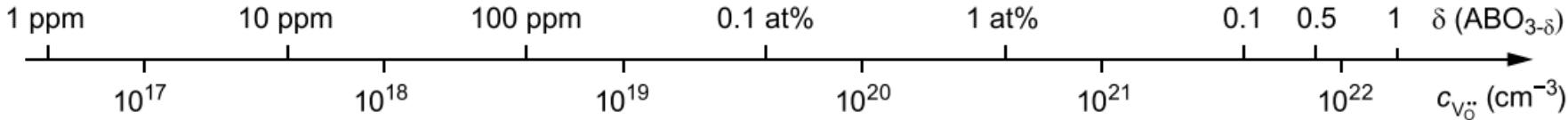
Ion conductor



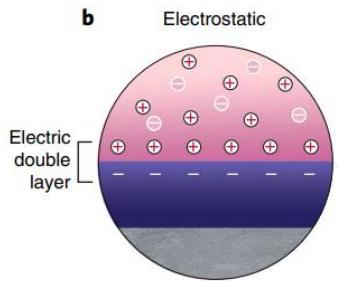
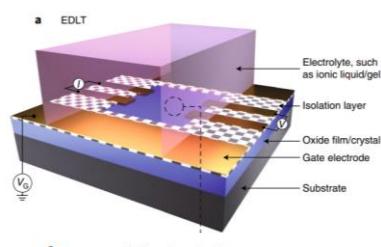
Fujimoto et al., Phys. Chem. Chem. Phys., 2013, 15, 8983--9006

Leighton et al., Nat. Mat., (2019), 18, 13-18

FET



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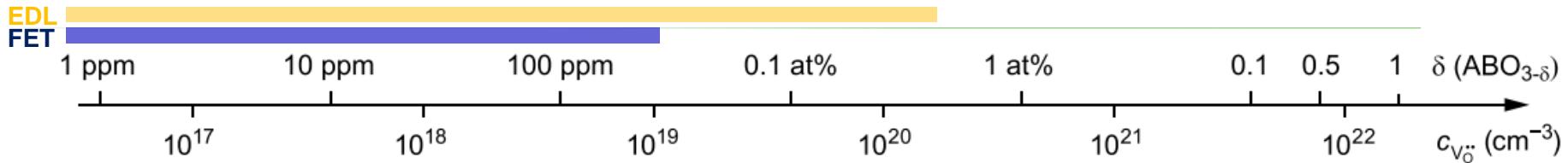
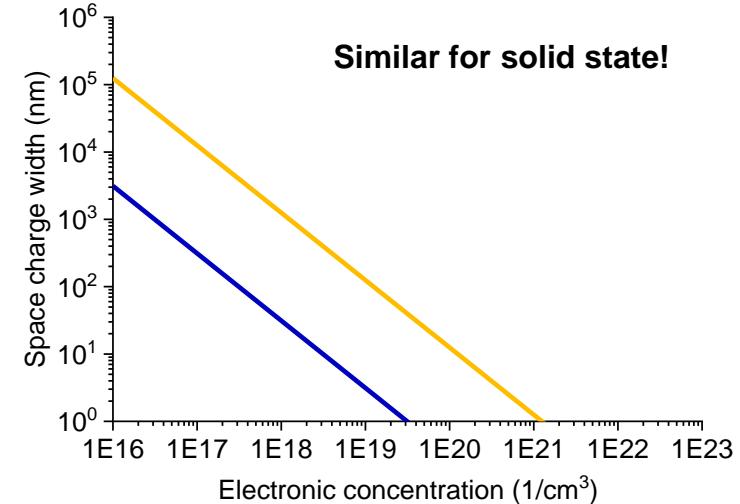


$$C = \frac{\epsilon_0 \epsilon_R}{d} \sim \frac{10 \epsilon_0}{10^{-7}} \sim 10 \mu F/cm^2$$

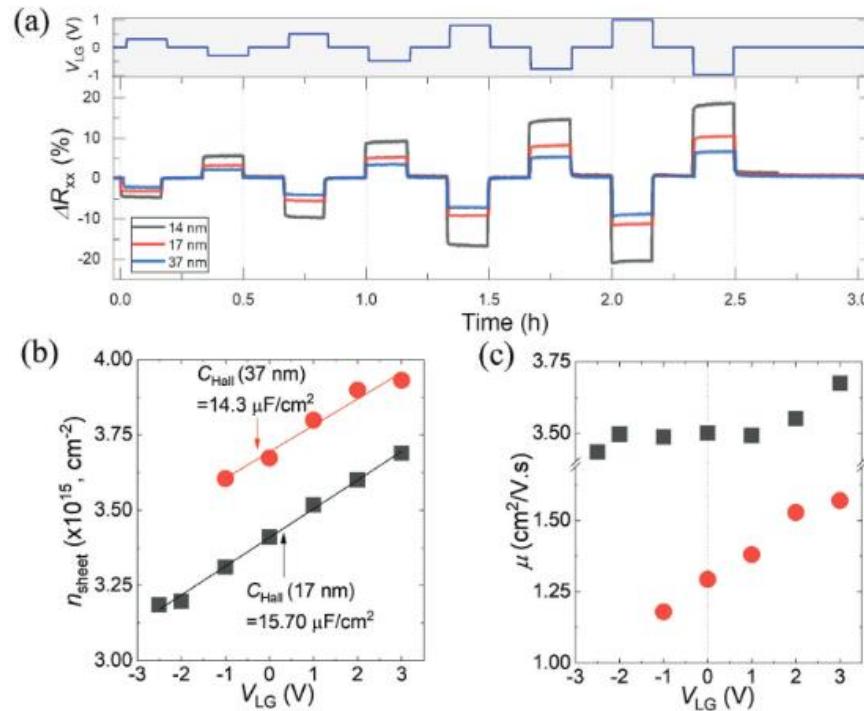
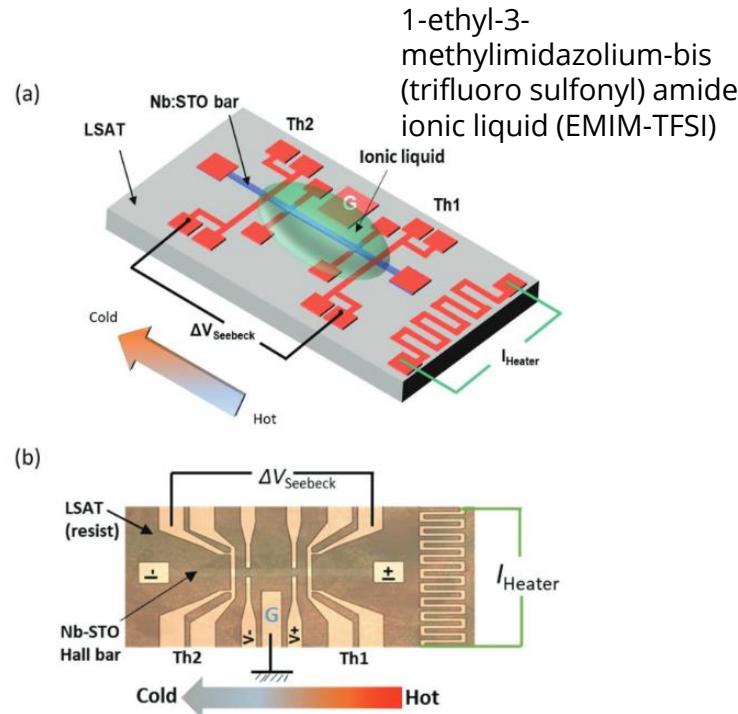
$$Q_c = C \cdot V \sim 10 \mu C/cm^2$$

$$\text{Switch time: } \tau = RC$$

Leighton et al., Nat. Mat., (2019), 18, 13-18

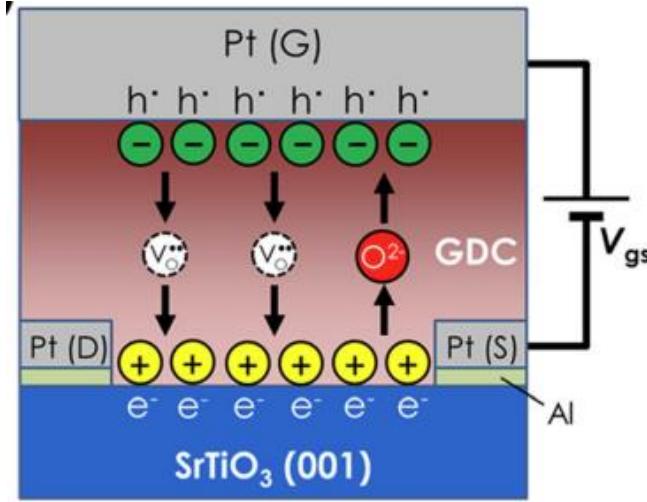


EDL modulation of charge carriers in Nb:SrTiO₃ thin films

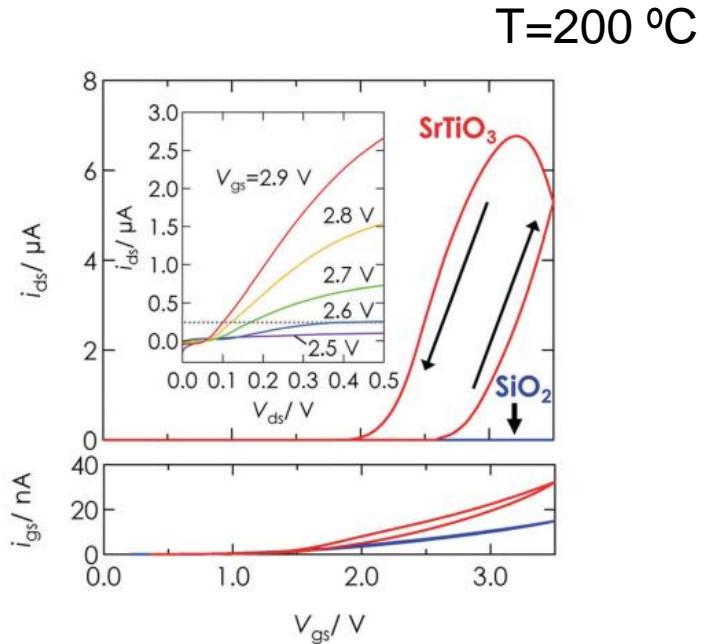


A. Chatterjee et al., Adv. Electron. Mater. 2024, 10, 2300683

EDL modulation in solid-state ionic conductors



$$C \sim 14 \mu\text{F}/\text{cm}^2$$

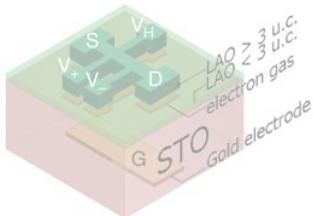


Takashi Tsuchiya et al., APPLIED PHYSICS LETTERS 103, 073110 (2013)

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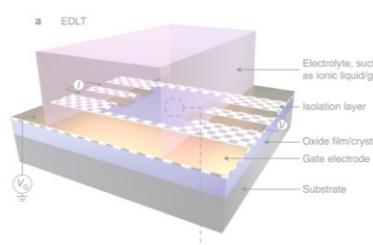
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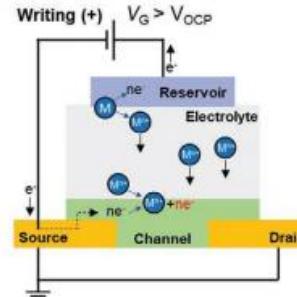
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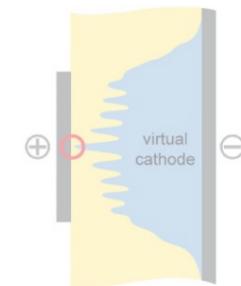
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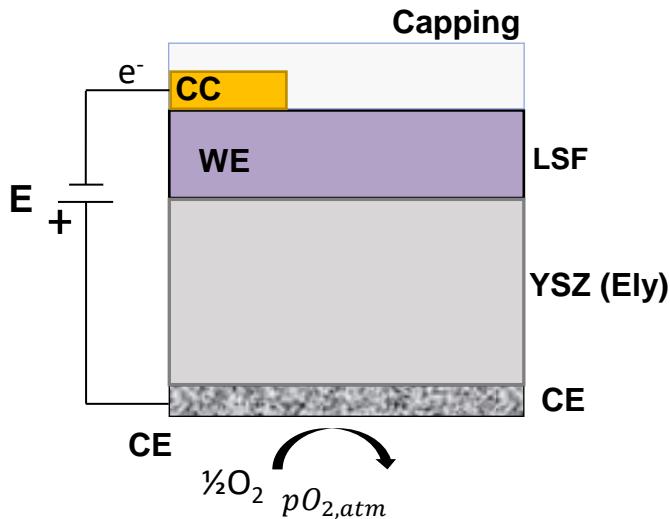
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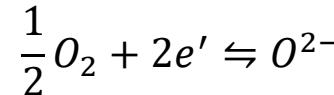
Electrolyte redox-ion insertion: a useful case study

Oxygen modulation in $\text{La}_{0.5}\text{Sr}_{0.5}\text{FeO}_{3-\delta}$ (LSF)



1st Ideal case:

- Surface capped
- No diffusion losses
- No insertion losses at LSF/YSZ
- Resistive electrolyte



Electrochemical potential

$$\mu_O + 2\tilde{\mu}_{e'} = \tilde{\mu}_{\text{O}^{2-}}$$

Same for gradients

$$\nabla\mu_O + 2\nabla\tilde{\mu}_{e'} = \nabla\tilde{\mu}_{\text{O}^{2-}}$$

At equilibrium (capping)

$$\nabla\tilde{\mu}_{\text{O}^{2-}} = 0 \quad \text{No flux}$$

Difference

$$\Delta\mu_O = -2\Delta\tilde{\mu}_{e'} = 2e\Delta E$$

$$\mu_o^{WE} = 2e\Delta E + \mu_o^{ATM} = 2e\Delta E + \frac{kT}{2} \ln\left(\frac{p\text{O}_{2,\text{atm}}}{1\text{bar}}\right)$$

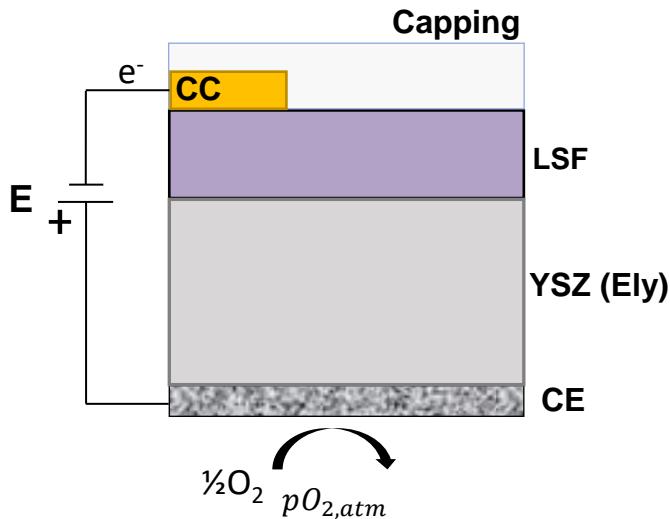
$$\mu_o^{ATM} = 1/2\mu_{\text{O}_2}^{ATM}$$

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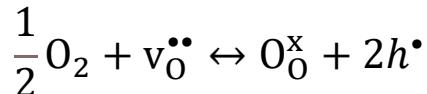
$$\mu_o^{WE} = 2e\Delta E + \frac{kT}{2} \ln\left(\frac{p\text{O}_{2,\text{atm}}}{1\text{bar}}\right)$$

Using the definition of chem. Pot
Equivalent $p\text{O}_2$ of the electrode:

$$\mu_o^{WE} = \frac{kT}{2} \ln\left(\frac{p\text{O}_{2,\text{eq}}}{1\text{bar}}\right)$$

$$\longrightarrow p\text{O}_{2,\text{eq}} = p\text{O}_{2,\text{atm}} \cdot \exp\left(\frac{4e\Delta E}{k_b T}\right)$$

Material's defect chemistry



$$K_{ox} = \frac{p\text{O}_{2,\text{eq}}^{1/2} [\text{v}_0^{\bullet\bullet}]}{[\text{O}_0^x][\text{h}^{\bullet}]^2}$$

Defect modulation by electrolyte ionic insertion

$$K_{\text{ox}} = \frac{pO_2^{1/2} [v_O^{\bullet\bullet}]}{[O_O^x]^2}$$

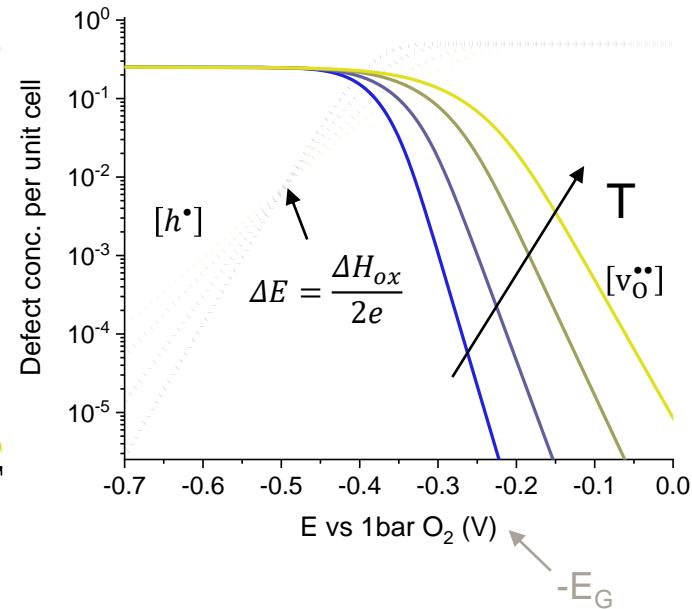
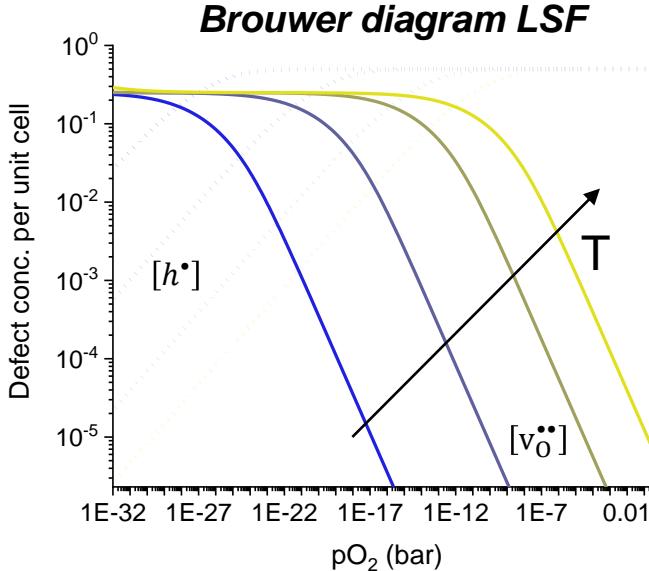
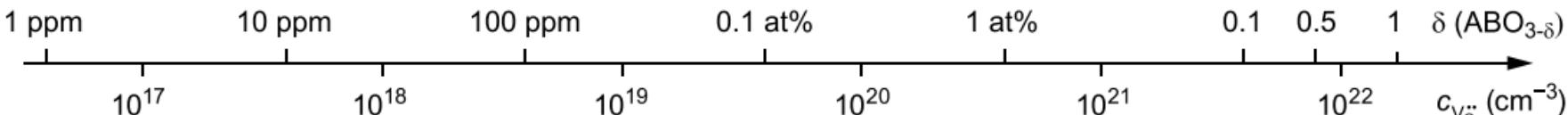
$$[\text{Sr}'_{\text{La}}] = [h^\bullet] + 2[v_O^{\bullet\bullet}]$$

$$[O_O^x] = 3 - [v_O^{\bullet\bullet}]$$

$$K_{\text{ox}} = \exp\left(\frac{\Delta S_{\text{ox}}}{k_b} - \frac{\Delta H_{\text{ox}}}{k_b T}\right)$$

$$pO_{2,\text{eq}} = pO_{2,\text{atm}} \cdot \exp\left(\frac{4e\Delta E}{k_b T}\right)$$

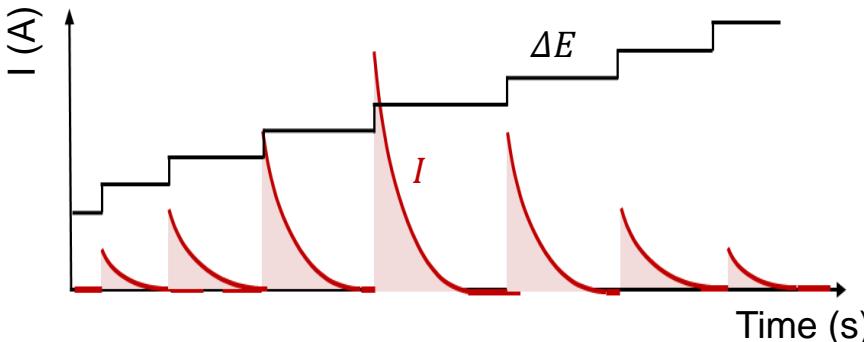
EII
EDL
FET



Current-Voltage relation and insertion characteristics

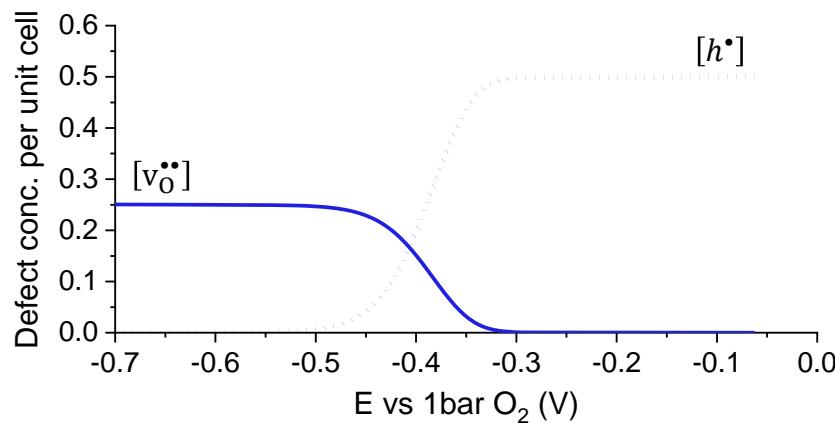
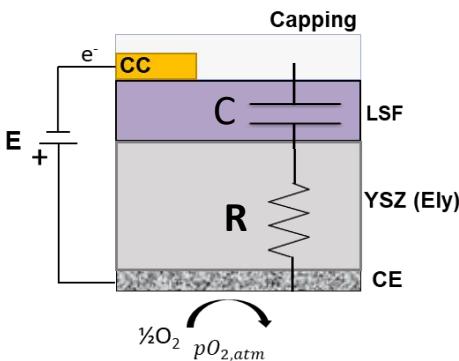
1st Ideal case:

- Surface capped
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- No insertion losses at LSF/YSZ
- Resistive electrolyte
- Fast electronic conduction



Relation vac-current

$$\Delta[v_0^{\bullet\bullet}] = -\frac{c_{LSF}^3}{2eV_{film}} \int_0^t I_G(t) dt$$



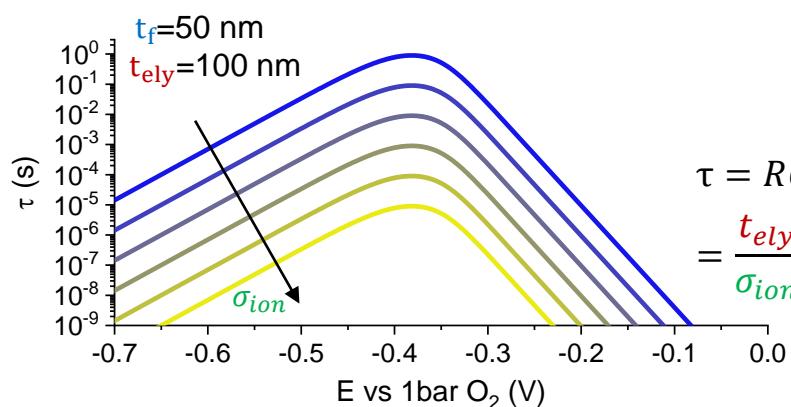
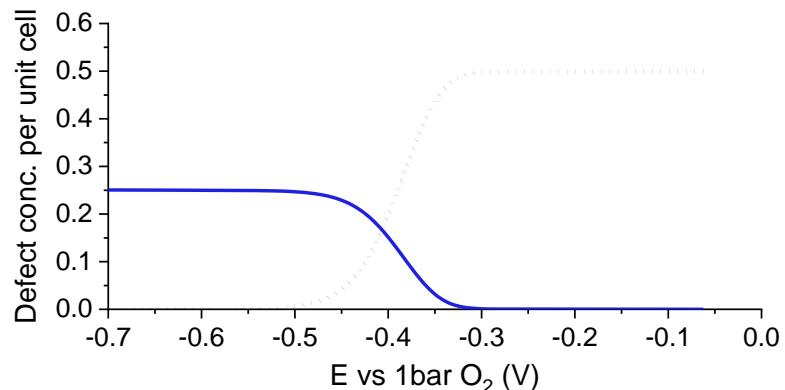
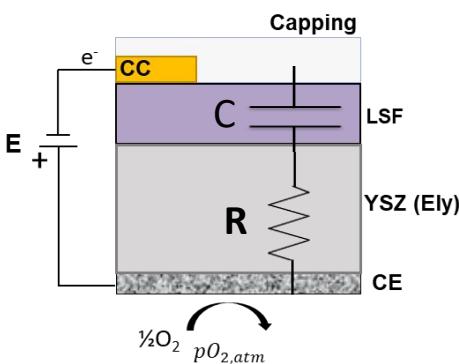
Time constant

$$\tau = RC_{chem}$$

Switching time

1st Ideal case:

- Surface capped
- No diffusion losses
- No insertion losses at LSF/YSZ
- Resistive electrolyte
- Fast electronic conduction



$$\tau = RC_{chem}$$

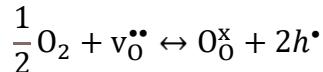
$$R = \frac{1}{\sigma_{ion}} \cdot \frac{t_{ely}}{A}$$

$$C_{chem} = -\frac{V_f}{c_{uc}^3} 4e^2 \cdot \frac{dc_o}{d\mu_0} = \\ = \frac{t_f \cdot A}{c_{uc}^3 k_b T} \cdot \left(\frac{1}{4[v_0^\bullet]} + \frac{1}{[h^\bullet]} \right)^{-1}$$

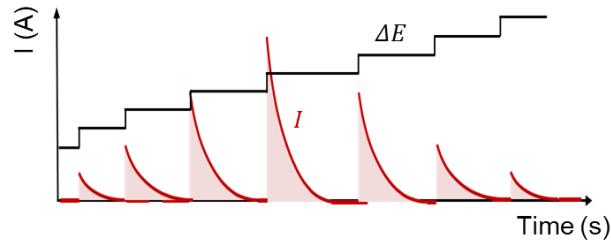
$$\tau = RC_{chem} \\ = \frac{t_{ely}}{\sigma_{ion}} \cdot t_f \cdot \frac{e^2}{c_{uc}^3 k_b T} \cdot \left(\frac{1}{4[v_0^\bullet]} + \frac{1}{[h^\bullet]} \right)^{-1}$$

Insertion potential ΔV

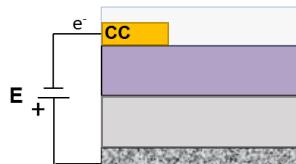
Insertion E:



$$\Delta E_i = -\frac{k_b T}{2e} \ln K_{ox}$$

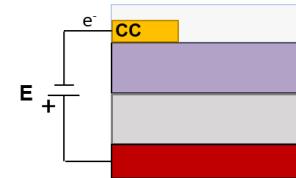


Asymmetric semi-open



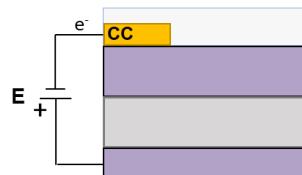
$\Delta V = \Delta E_i$ only depends on the material's equilibrium

Asymmetric battery-like



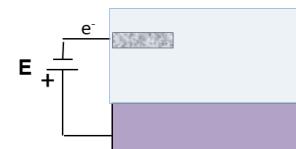
$\Delta V = \Delta E_G - \Delta E_C$

Symmetric battery-like



$\Delta V \sim 0$

Asymmetric with ely redox



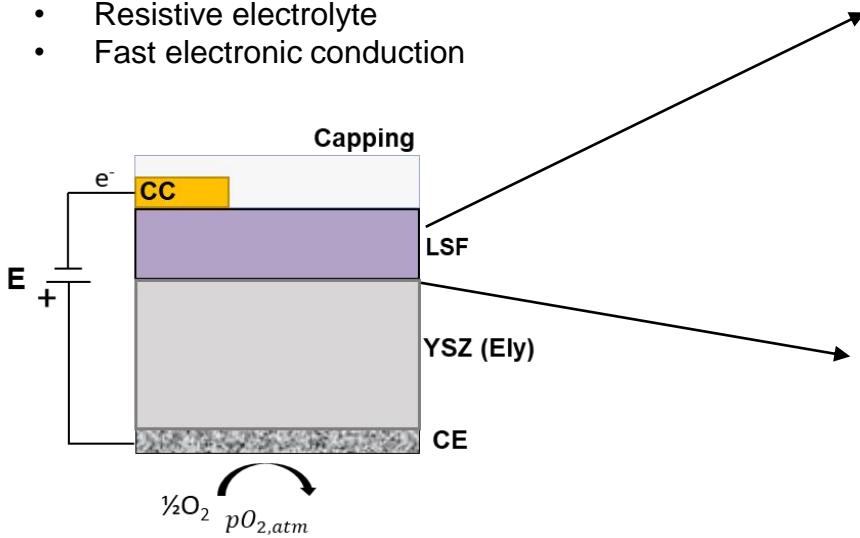
ΔE_i depends on the material's equilibrium and the redox reaction

$\Delta V = \Delta E_{red} - \Delta E_C$

Ion insertion in pseudo-real systems

2st Ideal case:

- Surface capped
- Diffusion losses
- Insertion losses
- Resistive electrolyte
- Fast electronic conduction



Ion transport:

$$\frac{\partial [v_O^{\bullet\bullet}]}{\partial t} = -\nabla \cdot (-D_{chem} \nabla [v_O^{\bullet\bullet}])$$

$$\tau \sim \frac{x^2}{2D_{chem}}$$

Diffusion slow down ions and creates conc. gradients

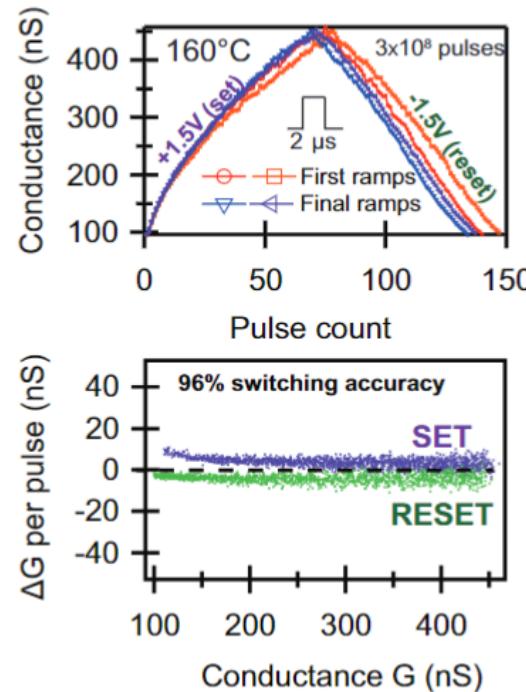
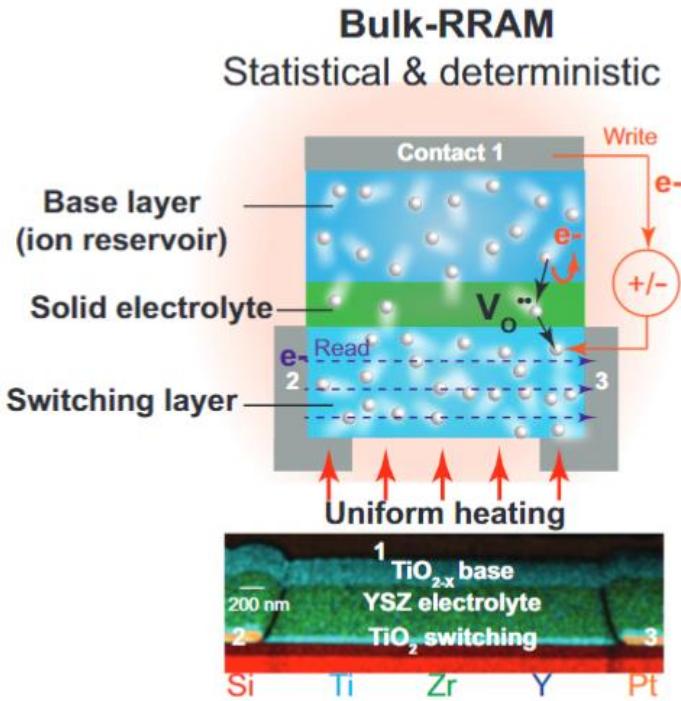
Ion insertion:

$$i = i_0 \left(\exp \left(\frac{\alpha_a F \eta}{RT} \right) - \exp \left(\frac{-\alpha_c F \eta}{RT} \right) \right)$$

$$\eta = \phi_{ele} - \phi_{ion} - E_{eq}([v_O^{\bullet\bullet}])$$

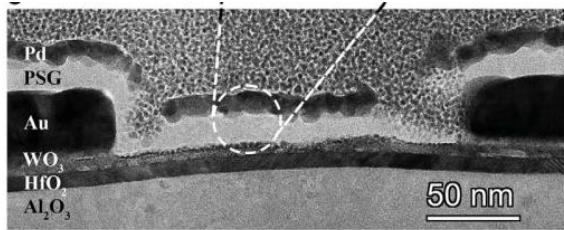
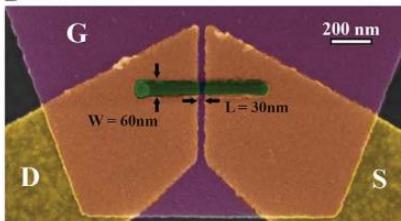
Ion insertion reduces the effects of an applied potential

Examples: Oxygen modulated Electrochemical ionic synapsis

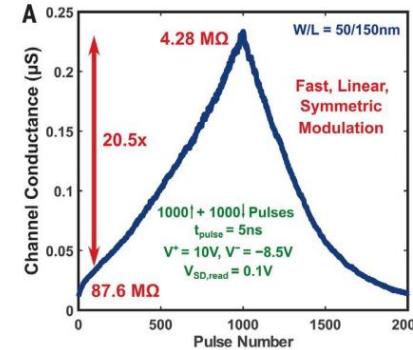


Nanosecond protonic programmable resistors

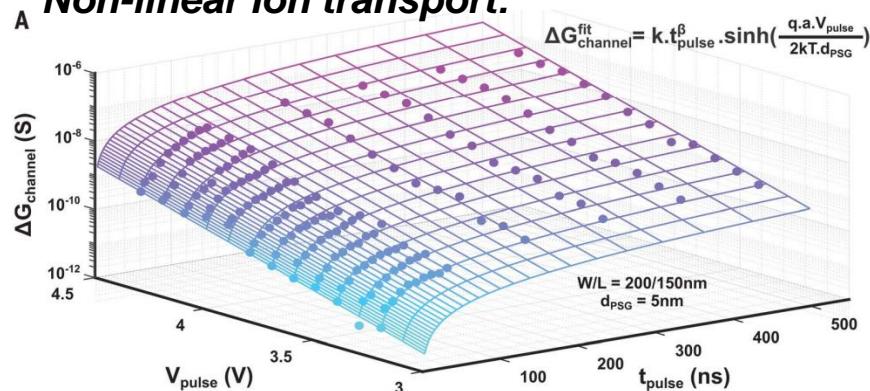
phosphosilicate glass as electrolyte



ns pulses modulation

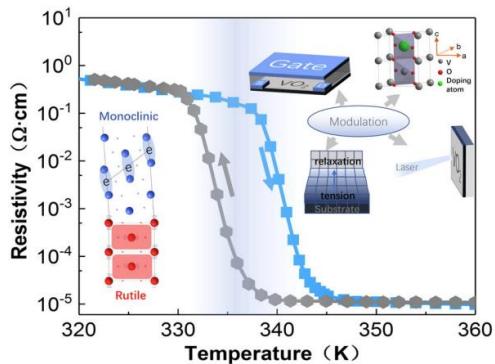


Non-linear Ion transport:



Oxygen vacancy modulation in ionic liquids

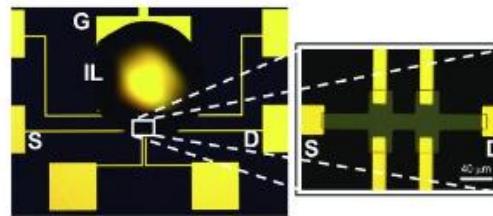
Metal insulator transition in VO_2



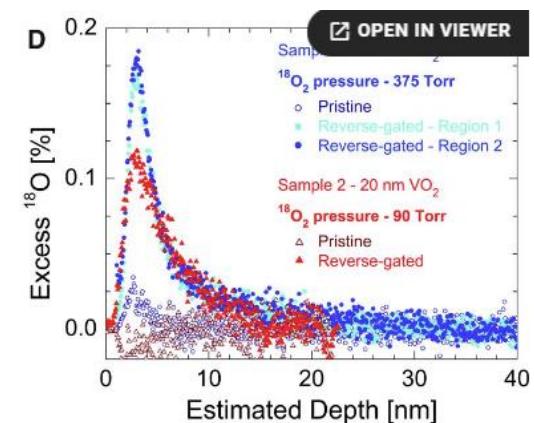
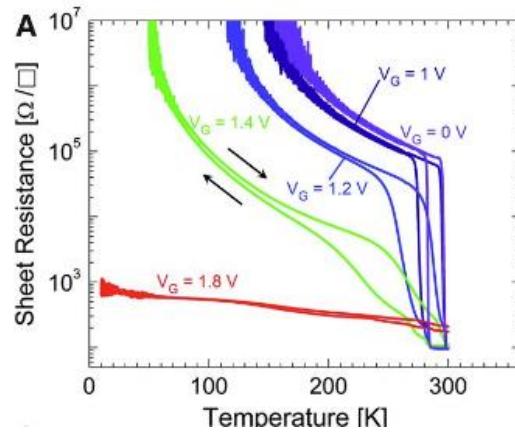
Shao et al. NPG Asia Materials (2018) 10: 581-605

Wegkamp, D. & Stähler, J, Prog. Surf. Sci. (2015) 90, 464–502

Oxygen vacancy creation in gated thin films

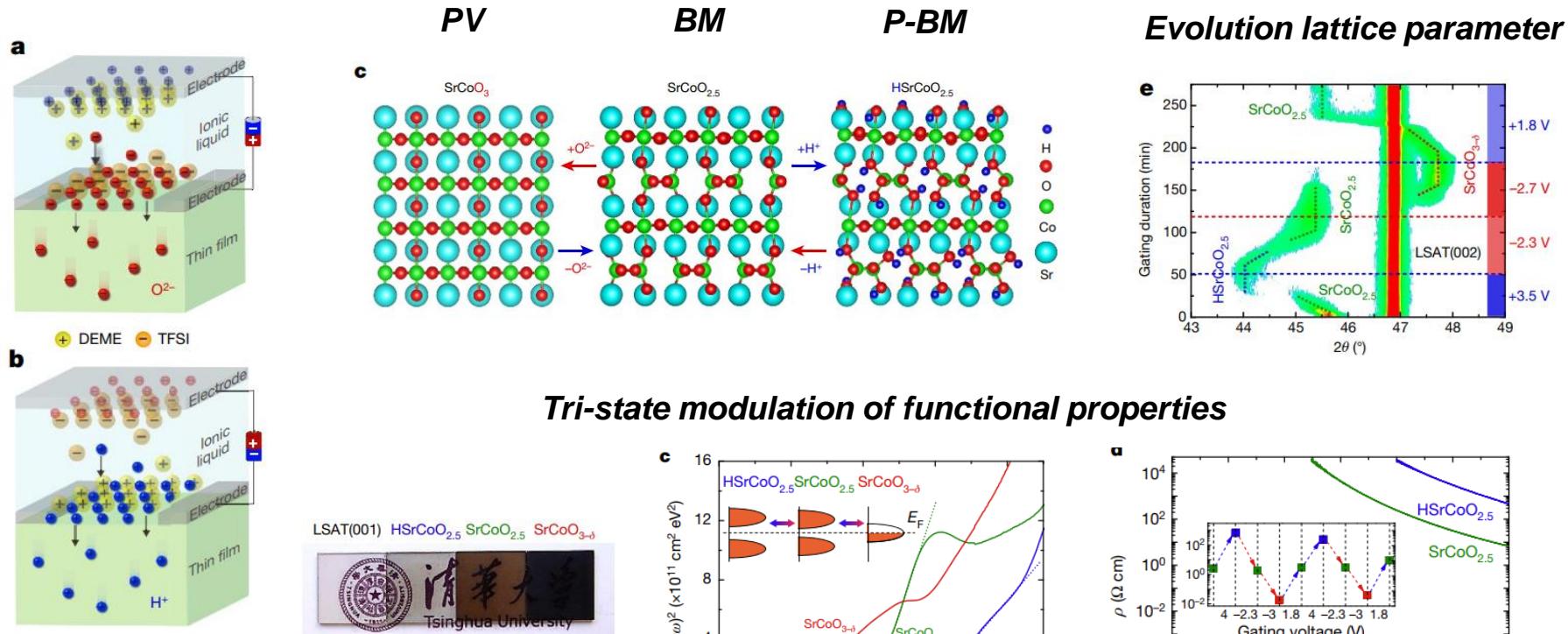


1-hexyl-3-methylimidazolium bis(trifluoromethylsulfonyl)-imide (HMIM-TFSI)



Jaewoo Jeong et al., Science, 339, 1402-1405(2013)

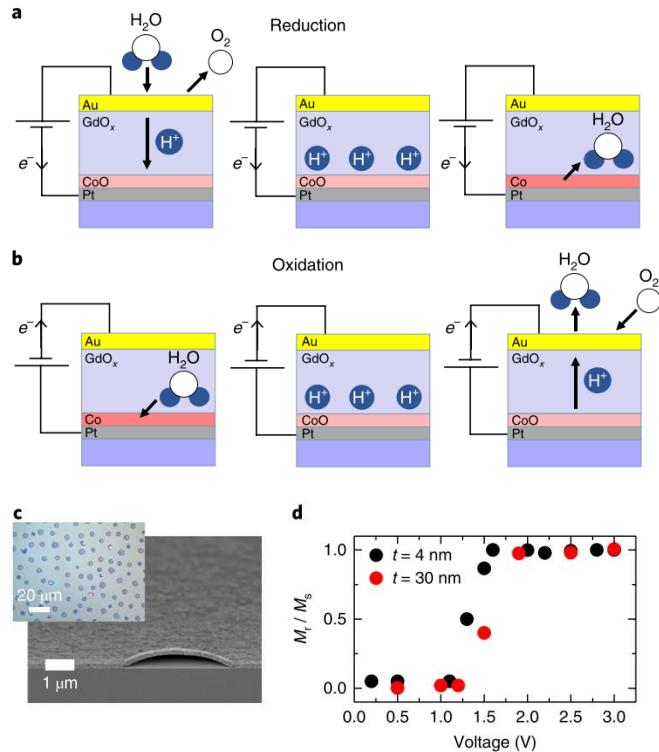
Oxygen vacancy and protonic modulation in ionic liquids



Oxygen and protons from water traces in the electrolyte

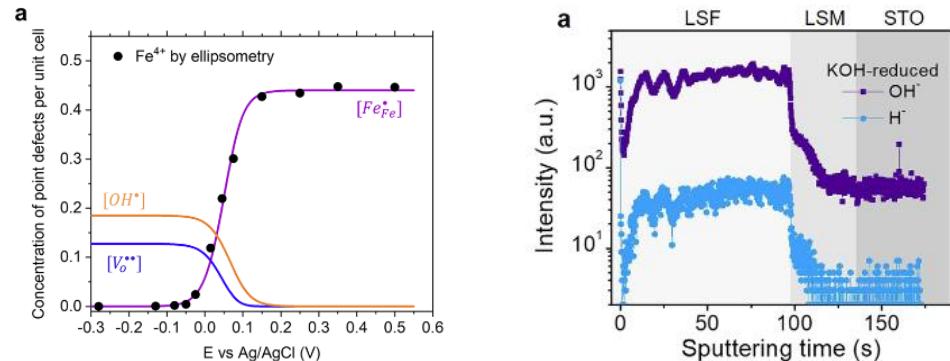
Protons and humidity may be very relevant!

Water splitting mediated oxidation of Co



Tan, A.J., et al., *Nature Mater* **18**, 35–41 (2019)

Protonation at RT of LSF in alkaline electrolytes



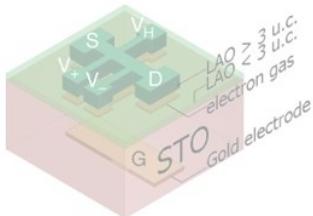
Tang et al., *ACS Appl. Mater. Interfaces* 2022, **14**, 18486–18497

- Water splitting (and proton diffusion) can promote oxidation (although it is not oxygen that is moving)
- Materials that do not host protons at high T can be protonated at RT (endothermic reaction): need of low T defect chemistry

How to modulate the ionic concentration of complex oxides?

Field effect

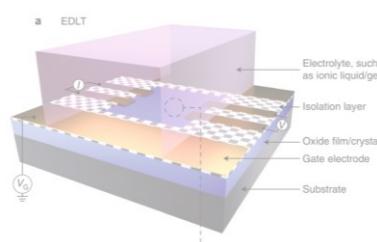
Application of E in the linear range through a dielectric



Caviglia et al, Nature (2008)
456, 624–627

Electrolyte double layer

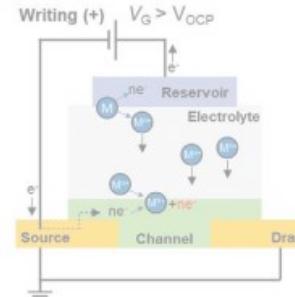
Application of E in the linear range through an ionic conductor



Leighton et al., Nat. Mat.,
(2019), 18, 13-18

Redox ionic insertion

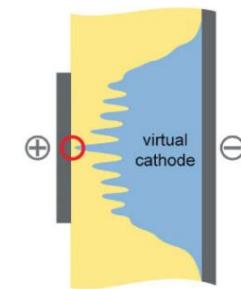
Application of E in the linear range through an ionic conductor



Huang et al., Adv. Mater.
2023, 35, 2205169

Resistive switching

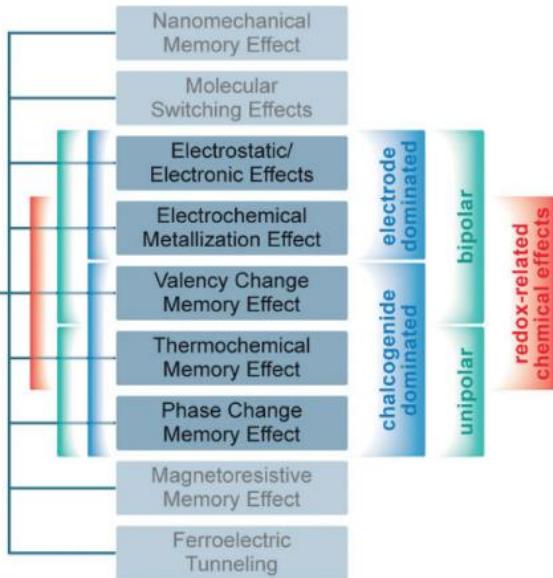
Application of large E directly to the material



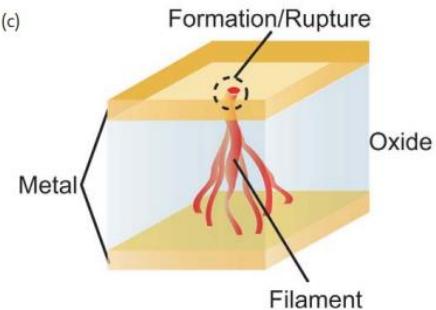
Waser et al., Adv. Mater.
2009, 21, 2632–2663

Redox-based resistive switching

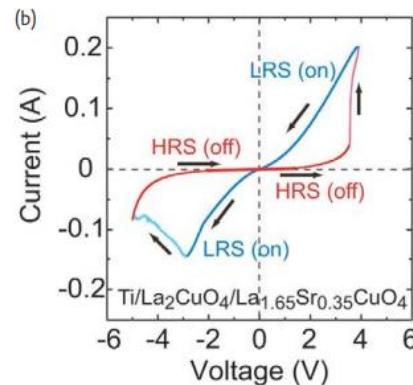
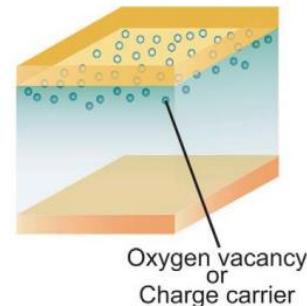
Resistive Switching



Filamentary



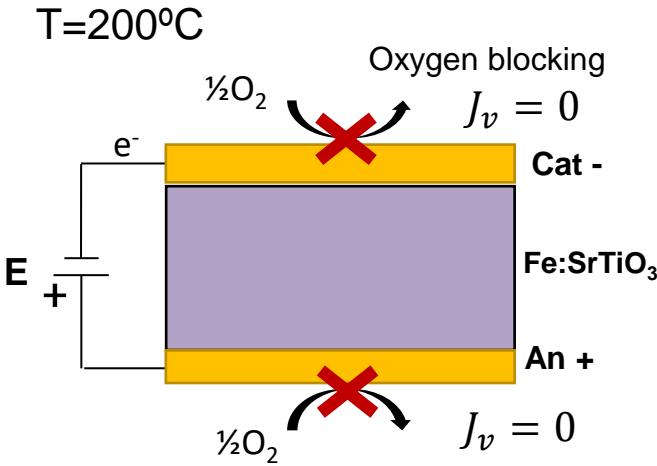
(d)



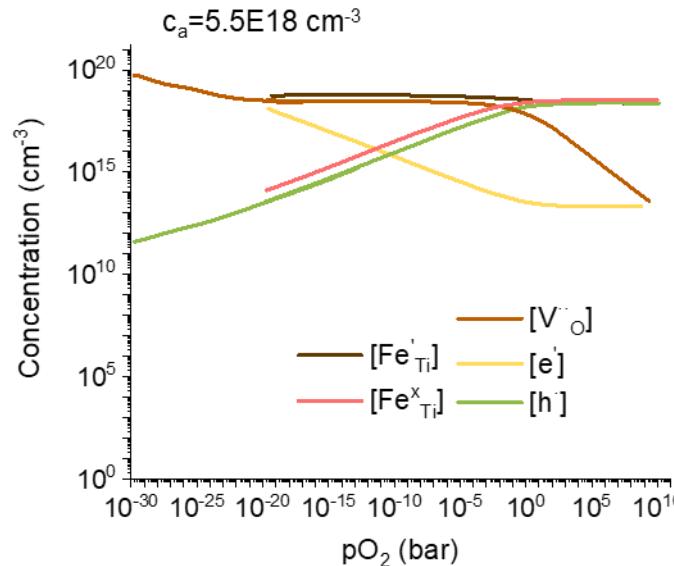
Waser et al., Adv. Mater. 2009, 21, 2632–2663

Akihito Sawa, Materials Today, 2008, 1, 6, 28-36

An example: defect modulation in SrTiO_3 under bias



Brouwer diagram: SrTiO_3 at 900°C



Defect model

$$K_{R2} = n^2 [\text{V}_\text{O}] \sqrt{p\text{O}_2}$$

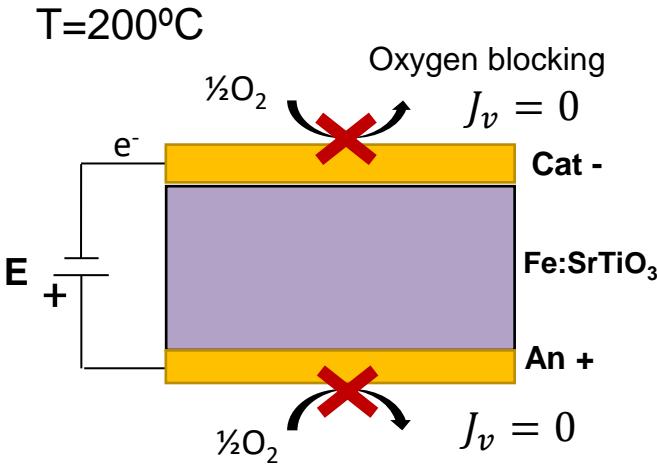
$$K_{R3} = [\text{Fe}'_\text{Ti}] p / [\text{Fe}^\times_\text{Ti}]$$

$$K_{R4} = np$$

Baiatu et al., J. Am. Ceram. Soc., 73 161 M63-73 (1990)

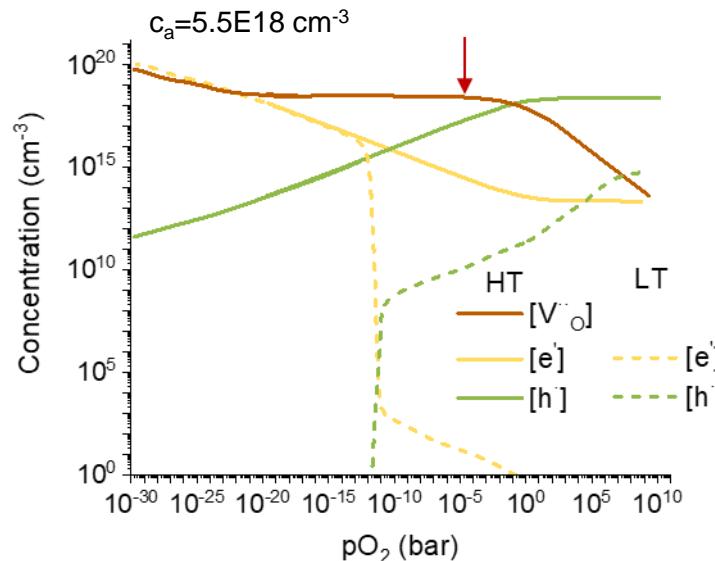
Wang et al., Acta Materialia 108 (2016) 229e240

An example: defect modulation in SrTiO_3 under bias



- Frozen oxygen equilibrium
- Hole trapping at LT
- Initial conditions: vacancies main defect

“Quenched” SrTiO_3 at 200°C



Defect model

$$K_{R2} = n^2 [\text{V}_\text{O}] \sqrt{p\text{O}_2}$$

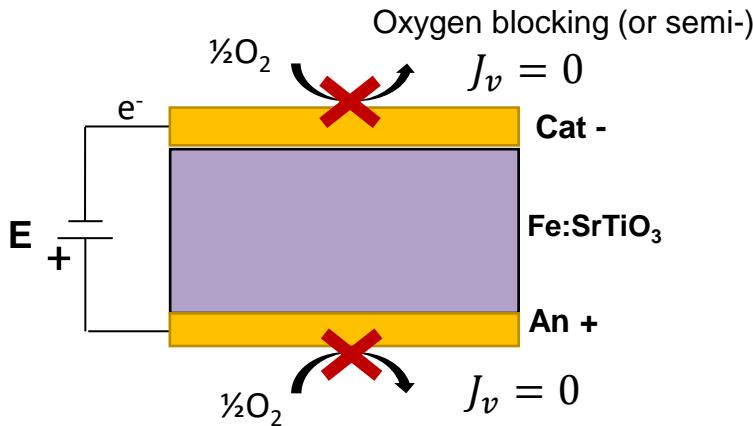
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An example: defect modulation in SrTiO_3 under bias



- Frozen oxygen equilibrium
- Hole trapping at LT
- Initial conditions: vacancies main defect

Nernst-Planck transport equation (dilute)

$$\text{Diffusion} \quad \text{Drift}$$

$$J_v = -2eD_v \cdot \frac{\partial [v_0^{\bullet\bullet}]}{\partial x} + 2e\mu_v [v_0^{\bullet\bullet}] \cdot E_x$$

$$\frac{\partial [v_0^{\bullet\bullet}]}{\partial t} = - \frac{\partial J_v}{\partial x}$$

Local equilibria: electrons and holes moves faster than oxygen vacancies and are always in equilibrium (from defect model)

$$\sigma(x, t) = 2e\mu_v [v_0^{\bullet\bullet}] + e\mu_n n + e\mu_p p$$

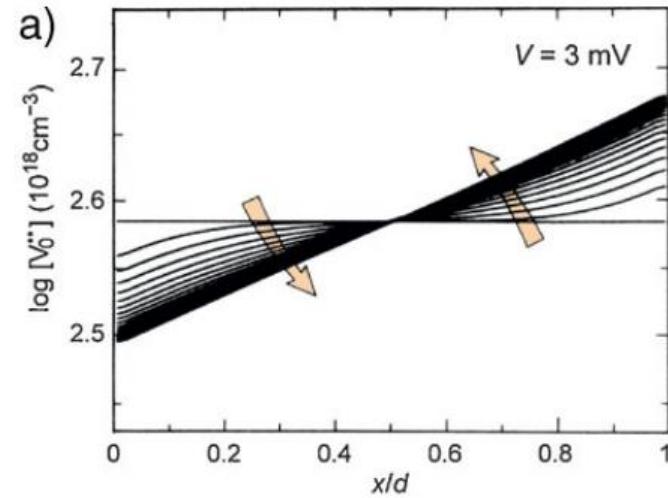
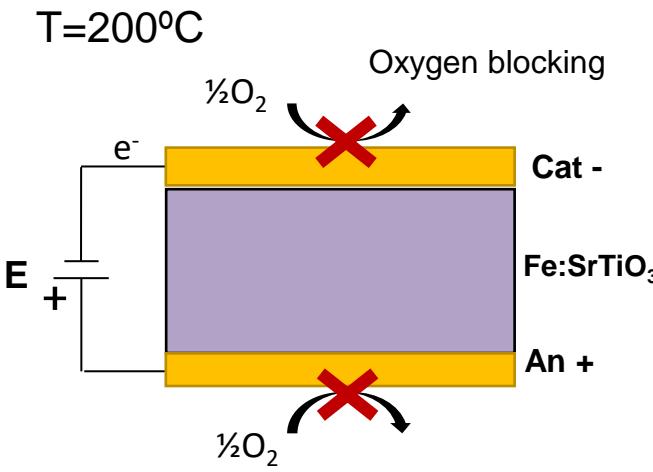
Maxwell equation $E_x(x, t) = \frac{J_{\text{drift}}}{\sigma(x, t)}$

Poisson equation $\rho(x, t) = \epsilon_0 \epsilon_r \frac{\partial E_x}{\partial x}$

Baiatu et al., J. Am. Ceram. Soc., 73 161 M63-73 (1990)

Wang et al., Acta Materialia 108 (2016) 229e240

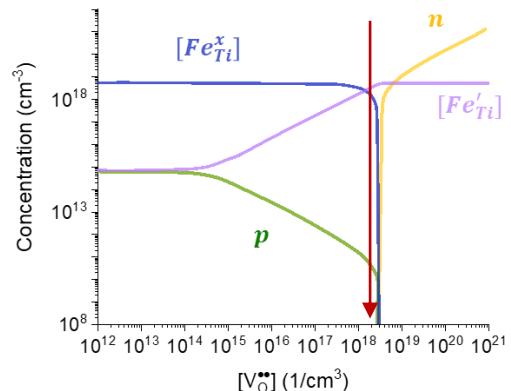
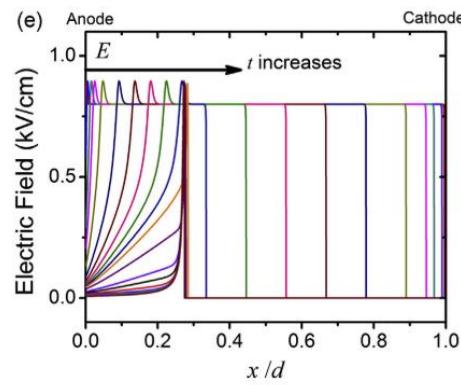
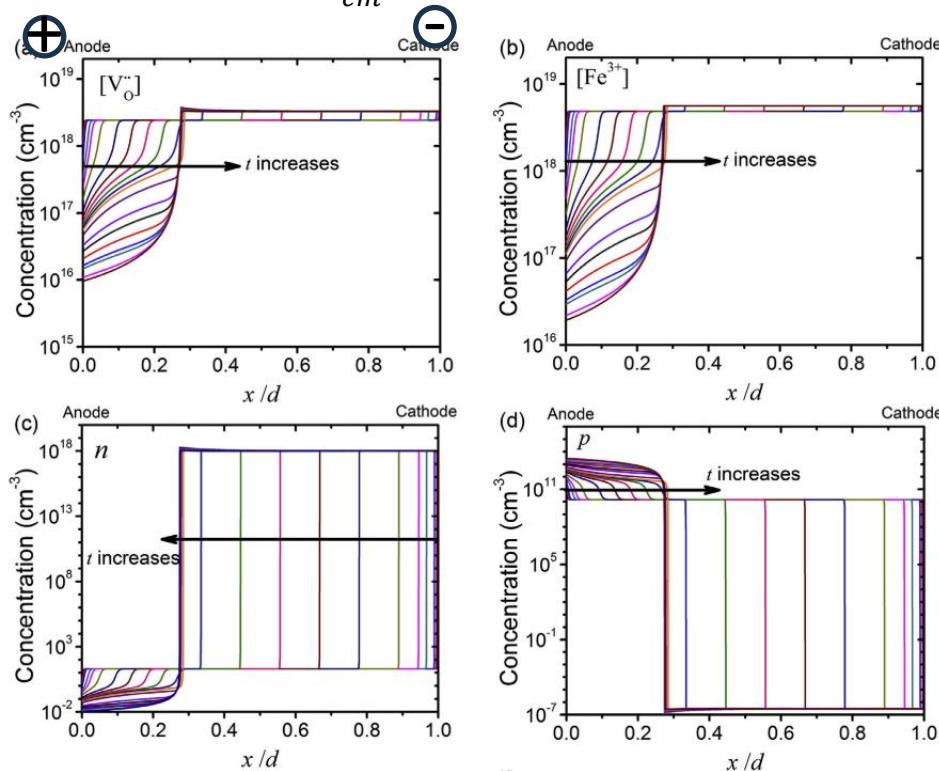
Small potentials: linear variation, no substantial changes



$$\frac{\partial [v_0^{\bullet\bullet}]}{\partial x} = -\frac{\sigma_v E_x}{2eD_v}$$

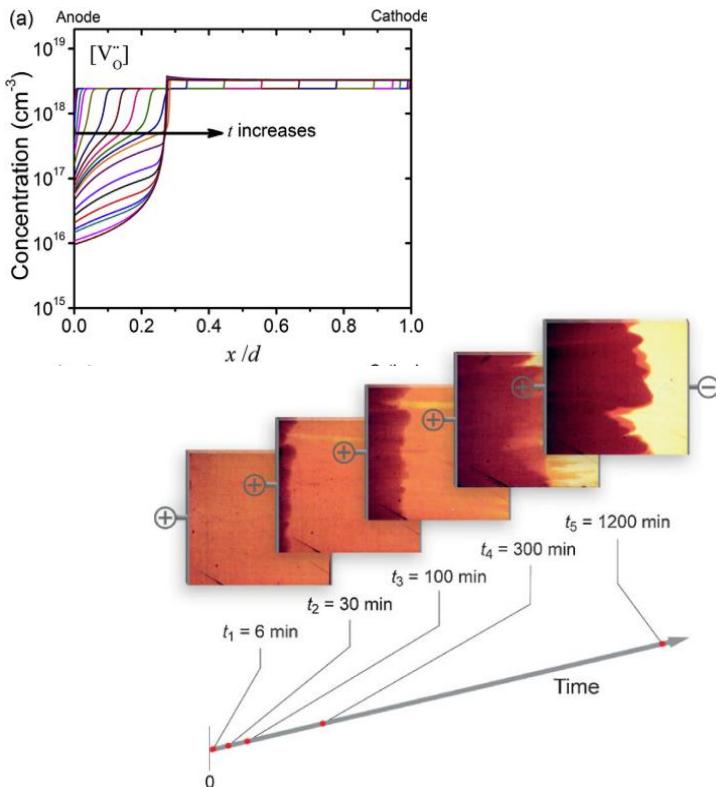
Evolution of the defect concentration after the application of large E

$$E = 240 \text{ V}, E_x = 800 \frac{\text{V}}{\text{cm}}, t = 0.3 \text{ cm}, T = 200^\circ\text{C}$$

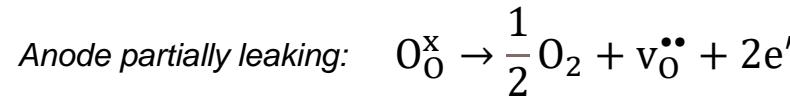


Consequences of the ion redistribution

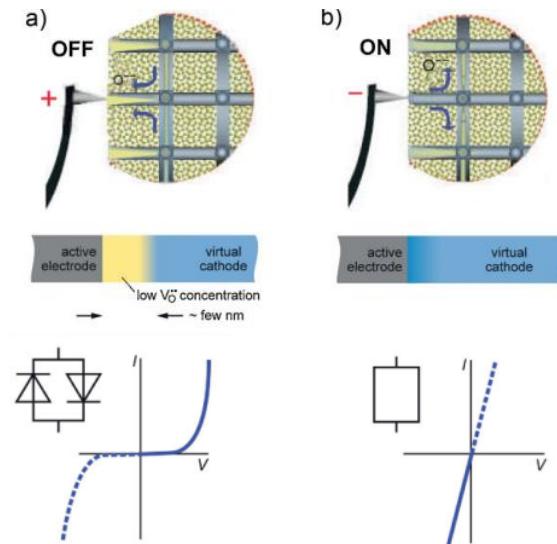
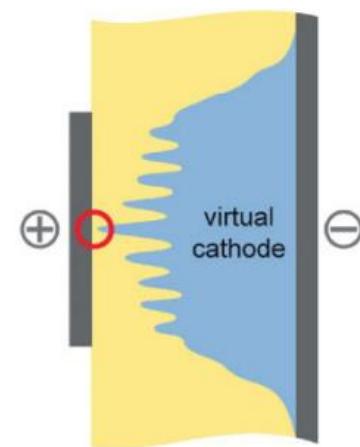
Change of color due to Fe^{4+}



Resistive switching



Injection of $\text{v}_0^{\bullet\bullet}$ that moves towards the cathode, a n-type region. Extended defects create filaments that grows till creating a contact between cathode and anode (ON).

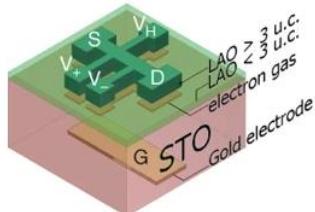


Recap

Iontronics: control of functional properties (electronic magnetic, optical,...) through the accumulation/ insertion/ variation of ion concentration for advanced devices such as: **Memristors, Electrochemical ion synapsis (programmable resistances), electrochromic windows, magnetoionic memories and transistors,...**

Field effect

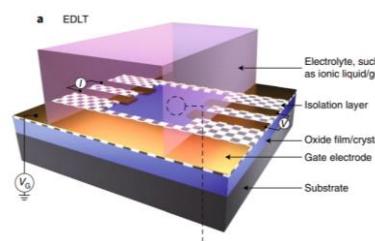
Application of E in the linear range through a dielectric



Caviglia et al, Nature (2008)
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Electrolyte double layer

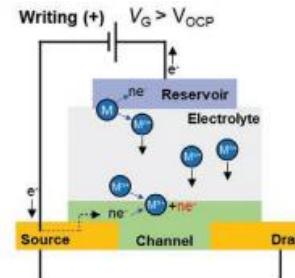
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Leighton et al., Nat. Mat.,
(2019), 18, 13-18

Redox ionic insertion

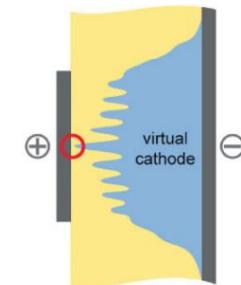
Application of E in the linear range through an ionic conductor



Huang et al., Adv. Mater.
2023, 35, 2205169

Resistive switching

Application of large E directly to the material



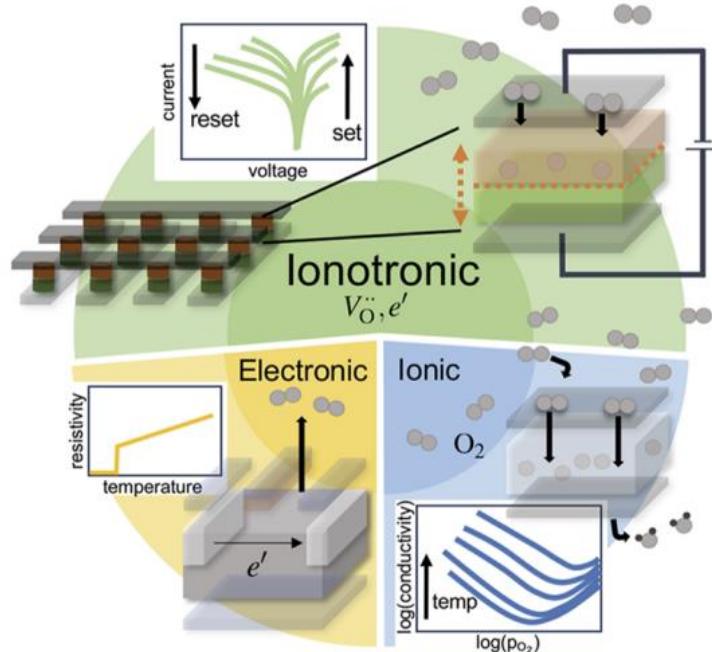
Waser el al., Adv. Mater.
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Thank you for your attention!

This project has funding from a Marie Skłodowska Curie Actions Postdoctoral Fellowship grant (101107093).

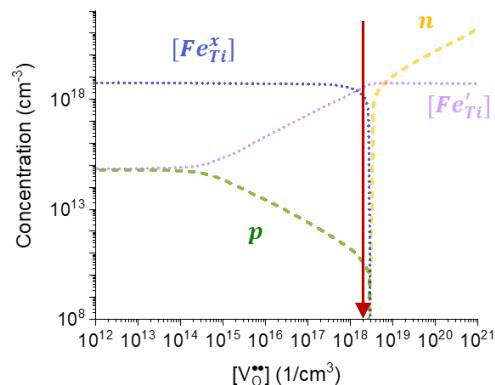
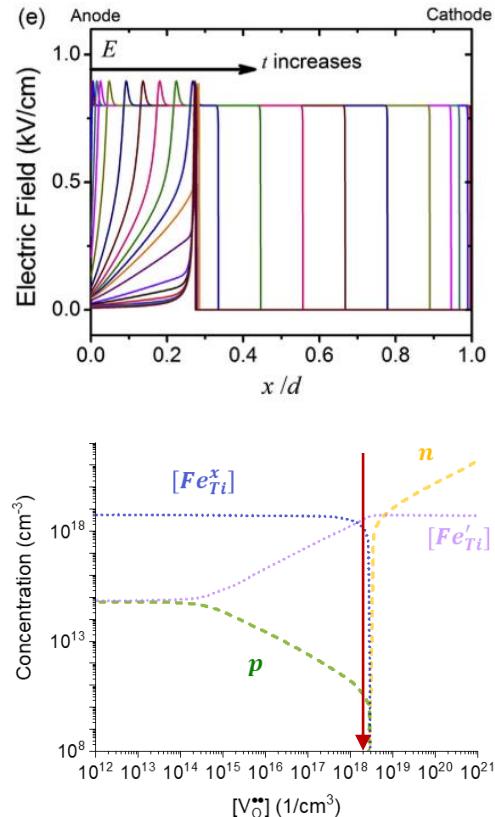
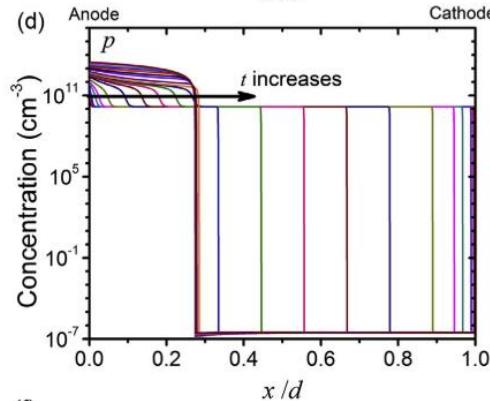
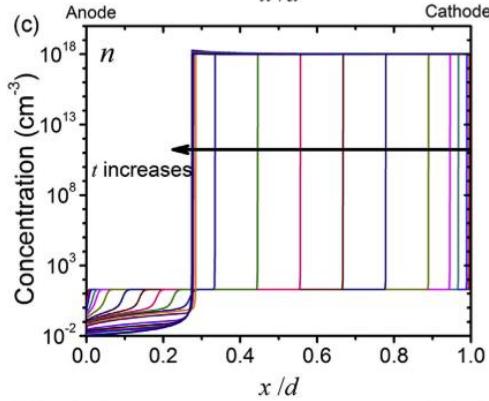
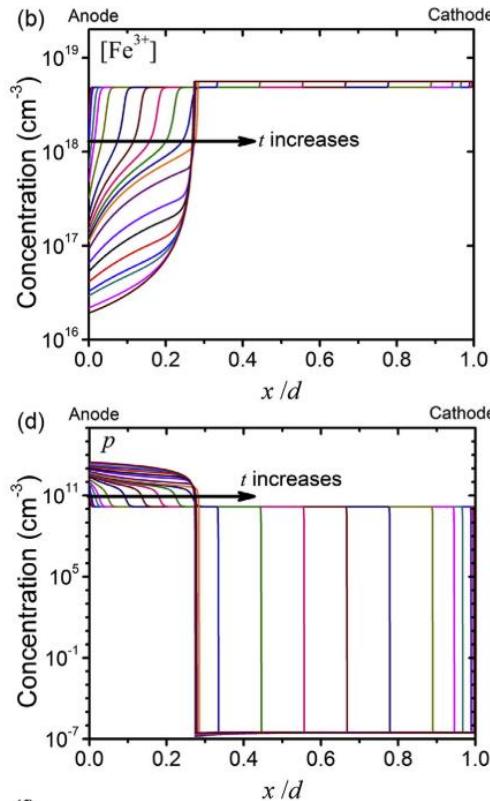
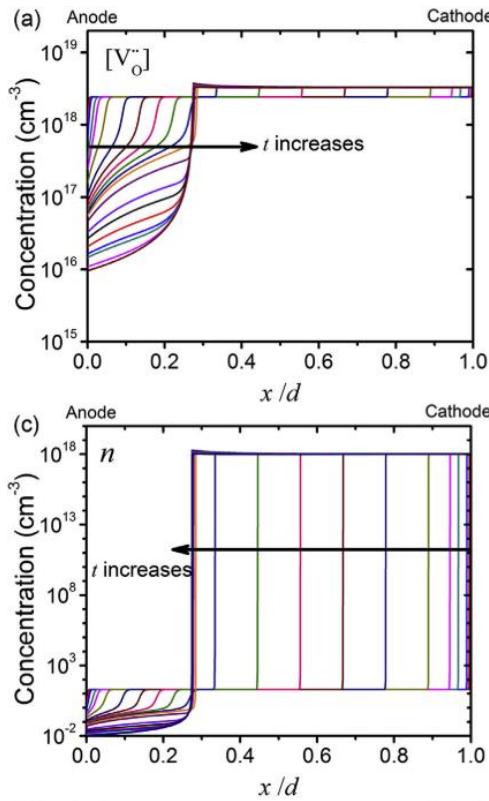


fchiabrera@irec.cat

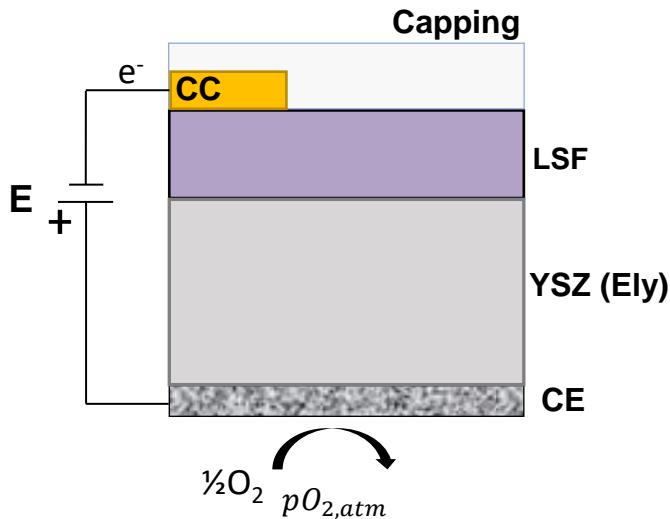


Wenderott et al., APL Mater. 12, 050901 (2024)

Evolution of the defect concentration after the application of large E

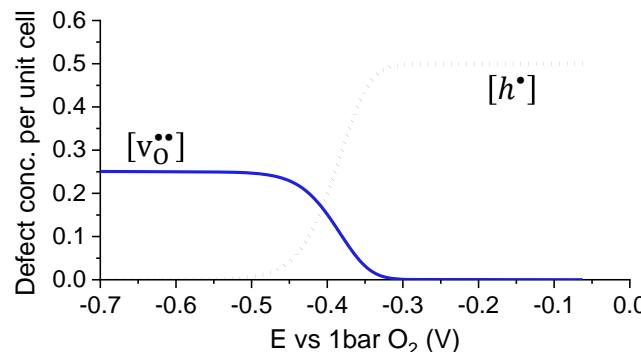
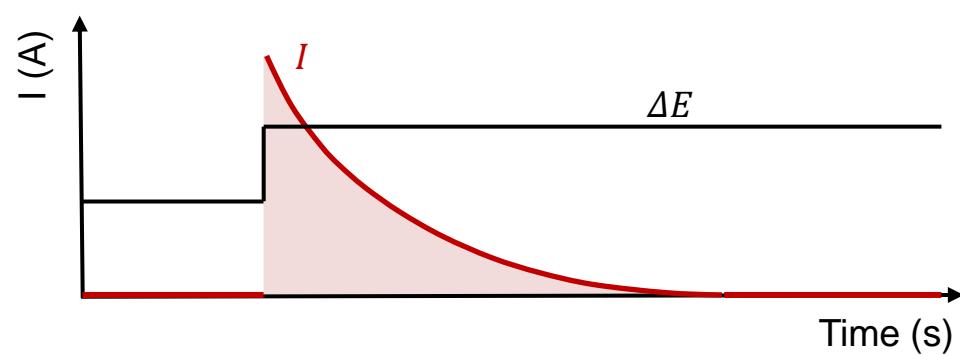


Oxygen modulation in $\text{La}_{0.5}\text{Sr}_{0.5}\text{FeO}_{3-\delta}$ (LSF)



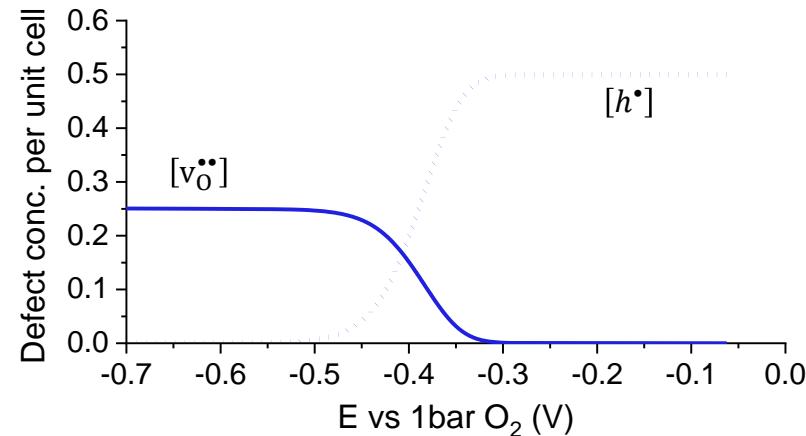
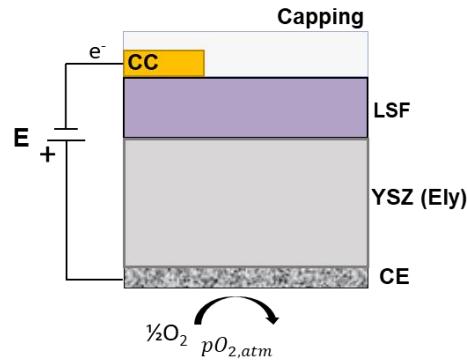
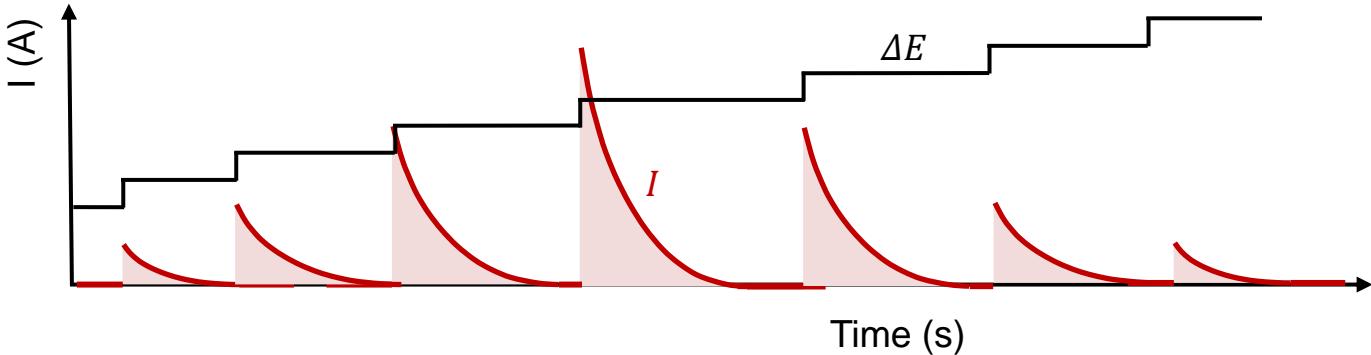
1st Ideal case:

- Surface capped
- No diffusion losses
- No insertion losses at LSF/YSZ
- Resistive electrolyte



1st Ideal case:

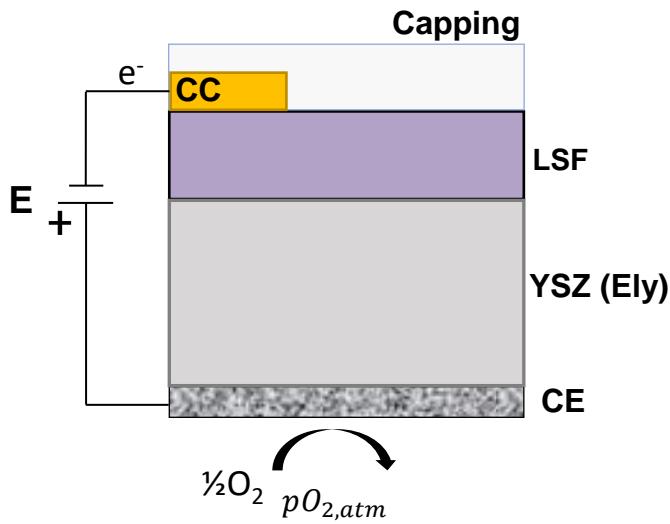
- Surface capped
- No diffusion losses
- No insertion losses at LSF/YSZ
- Resistive electrolyte



$$\Delta[v_0^{\bullet\bullet}] = -\frac{c_{LSF}^3}{2eV_{film}} \int$$

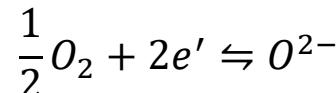
Electrolyte redox-ion insertion: a useful case study

Oxygen modulation in $\text{La}_{0.5}\text{Sr}_{0.5}\text{FeO}_{3-\delta}$ (LSF)



1st Ideal case:

- No oxygen incorporation on the surface (capped)
- No diffusion losses
- No insertion losses at LSF/YSZ
- CE no resistive



$$\mu_O + 2\tilde{\mu}_{e'} = \tilde{\mu}_{O^{2-}}$$

$$\Delta\mu_O + 2\Delta\tilde{\mu}_{e'} = \Delta\tilde{\mu}_{O^{2-}}$$

$$\nabla\tilde{\mu}_{O^{2-}} = 0 \quad \text{No flux}$$

$$\Delta\mu_O = -2\Delta\tilde{\mu}_{e'} = 2e\Delta E$$

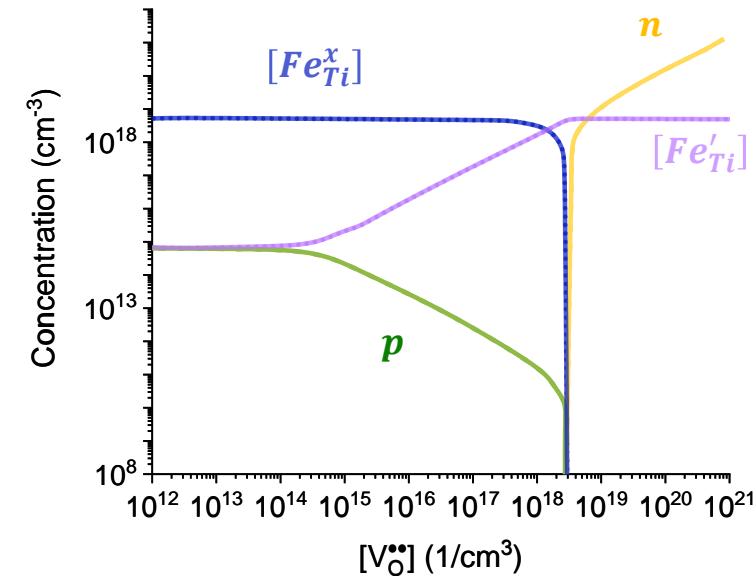
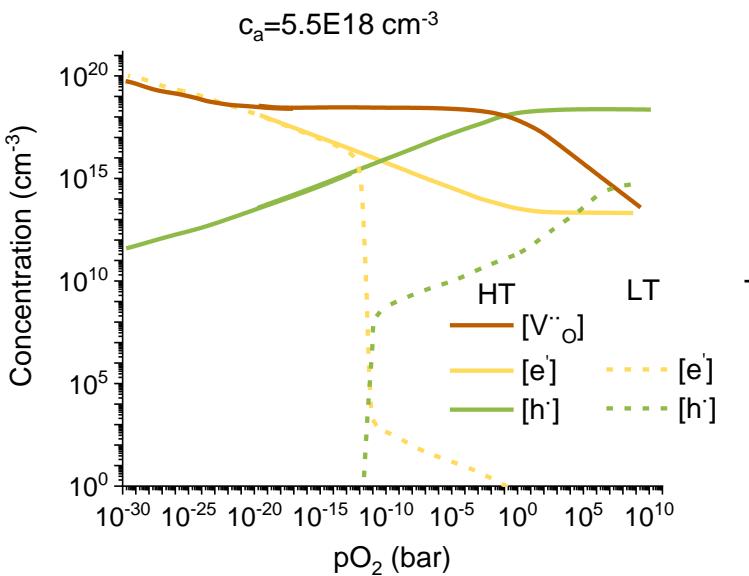
$$\mu_o^{LSF} = 2e\Delta E + \mu_o^{ATM} = 2e\Delta E + \frac{kT}{2} \ln\left(\frac{p_{O_2,atm}}{1\text{bar}}\right)$$

$$\mu_o^{ATM} = 1/2\mu_{O_2}^{ATM}$$

Same for differences

Defect concentration as a function of the oxygen vacancy concentration

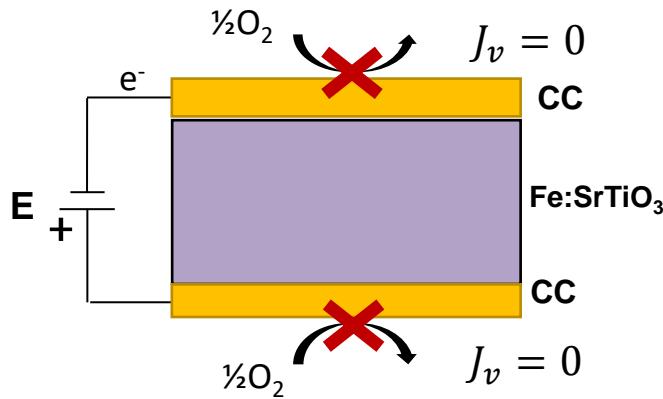
*Quenched Brouwer
diagram of $SrTiO_3$*



- Frozen $[v_O^{\bullet\bullet}]$
- Hole trapping at LT

Low potentials (small variation from equilibrium)

Oxygen blocking (or semi-)



Nernst-Planck transport
equation (dilute)

$$\text{Diffusion} \quad J_i = -z_i e D_i \cdot \frac{\partial [i]}{\partial x} + z_i e \mu_i [i] \cdot \frac{\partial E}{\partial x} \quad i = v_0^{\bullet\bullet}, h^{\bullet}, e'$$

$$\frac{\partial [v_0^{\bullet\bullet}]}{\partial x} = \mu_i [v_0^{\bullet\bullet}] \cdot \frac{\partial E}{\partial x}$$

Assumption
and are al

Steady state:

Baiatu et al., J. Am. Ceram. Soc., 73 161 M63-73 (1990)

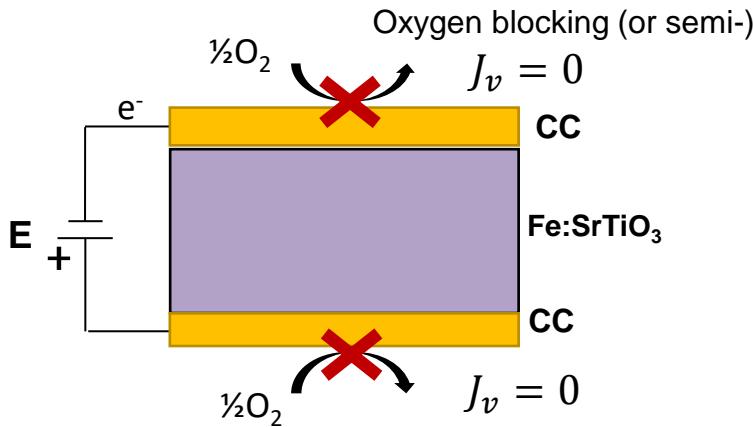
Wang et al., Acta Materialia 108 (2016) 229e240

Nernst-Planck transport equation (dilute)

$$\text{Diffusion} \quad J_i = -z_i e D_i \cdot \frac{\partial [i]}{\partial x} + z_i e \mu_i [i] \cdot \frac{\partial E}{\partial x}$$

$$\text{Drift} \quad \frac{\partial [i]}{\partial t} = - \frac{\partial J_i}{\partial x}$$

$$i = v_0^\bullet, h^\bullet, e'$$



Assumption: electrons and holes moves faster than oxygen vacancies and are always in equilibrium

Steady state:

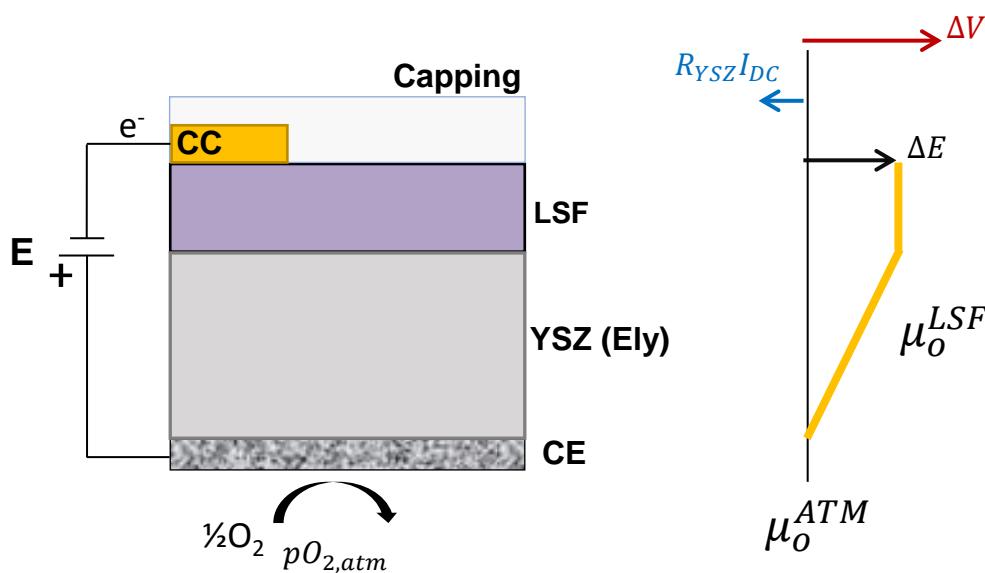
Low E

Baiatu et al., J. Am. Ceram. Soc., 73 161 M63-73 (1990)

Wang et al., Acta Materialia 108 (2016) 229e240

Electrolyte redox-ion insertion: a useful case study

Oxygen modulation in $\text{La}_{0.5}\text{Sr}_{0.5}\text{FeO}_{3-\delta}$ (LSF)



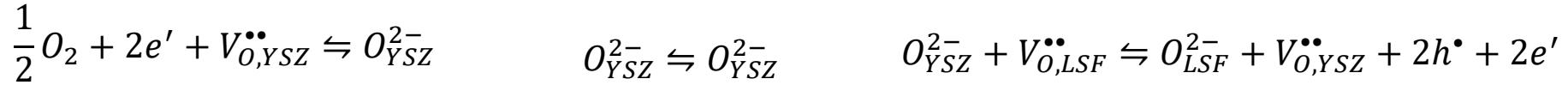
1st Ideal case:

- No oxygen incorporation on the surface (capped)
- No diffusion losses
- No insertion losses at LSF/YSZ
- CE no resistive

$$\mu_o^{ATM} = 1/2 \mu_{o_2}^{ATM} = \frac{kT}{2} \ln\left(\frac{p\text{O}_{2,\text{atm}}}{1\text{bar}}\right)$$

$$\mu_o^{LSF} = 2F\Delta E + \frac{RT}{2F} \ln\left(\frac{p\text{O}_{2,\text{atm}}}{1\text{bar}}\right)$$

$$\Delta E = \Delta V - R_{YSZ}I_{DC}$$



But first a useful recap:

General chemical reaction:

$$\sum_i^R \nu_i R_i \Leftrightarrow \sum_j^R \nu_j P_j$$

$$\Delta G = \sum_i^P \mu_i \nu_i - \sum_j^R \mu_j \nu_j$$

Inserting def. of chemical potential:

$$\Delta G = G_0 + RT \ln\left(\frac{\prod_i^P (c_i)^{\nu_i}}{\prod_j^R (c_j)^{\nu_j}}\right)$$

Equilibrium: $\Delta G = 0$

Electrochemical reaction:

$$\sum_i^R \nu_i R_i^q \Leftrightarrow \sum_j^R \nu_j P_j^q$$

$$\Delta G = \sum_i^P \tilde{\mu}_i \nu_i - \sum_j^R \tilde{\mu}_j \nu_j$$

Inserting def. of electrochemical potential:

$$\eta = \eta_0 + \frac{RT}{z_i F} \ln\left(\frac{\prod_i^P (c_i)^{\nu_i}}{\prod_j^R (c_j)^{\nu_j}}\right)$$

Equilibrium: $\eta = 0$

$$\mu_i = \left(\frac{\partial G}{\partial n_i}\right)_{T,p,n_1,n_2,\dots}$$

$$\mu_i = \mu_i^0 + RT \ln(a_i)$$

$$gas \quad a_{O_2} = pO_2$$

$$defect \quad a_i = c_i$$

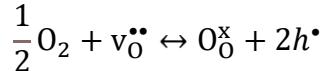
Electrochemical potential

$$\tilde{\mu}_i = \mu_i + z_i F \eta$$

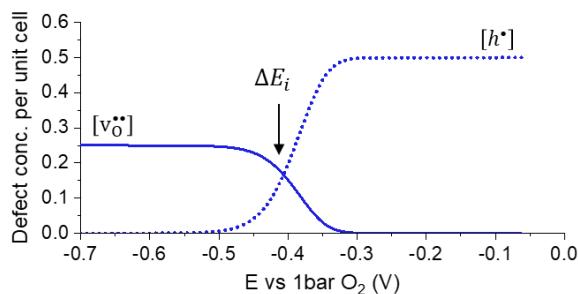
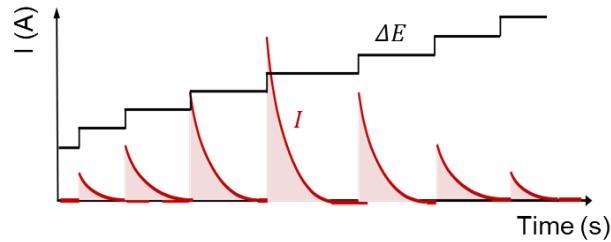
$$\eta = \frac{\Delta G}{z_i F}$$

About the insertion potential

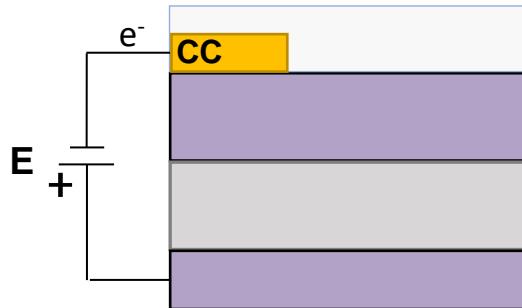
Insertion E:



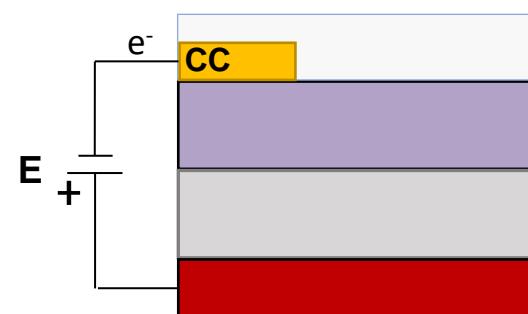
$$\Delta E_i = -\frac{k_b T}{2e} \ln K_{ox}$$



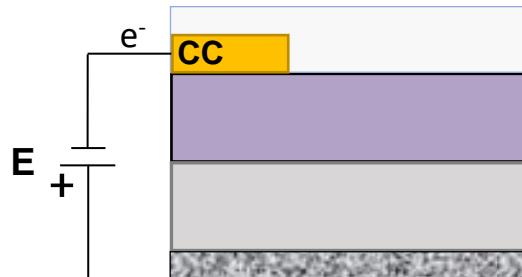
Symmetric battery-like



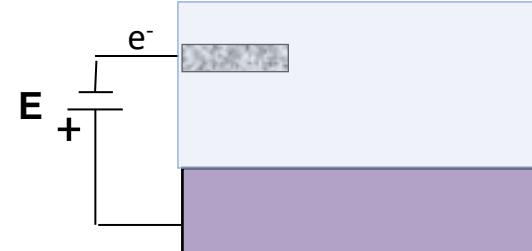
Asymmetric battery-like



Asymmetric semi-open



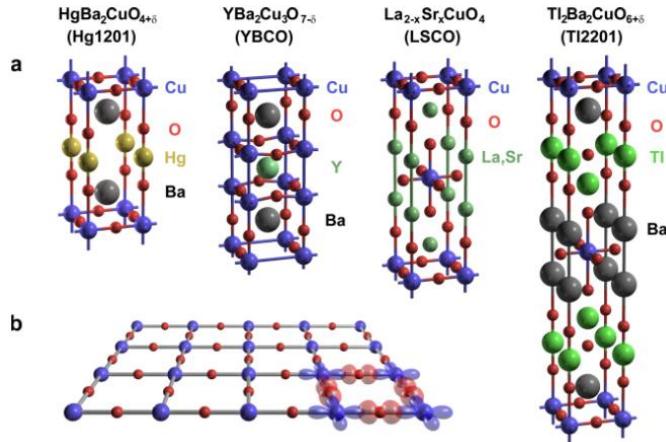
Asymmetric with ely redox



Liquid

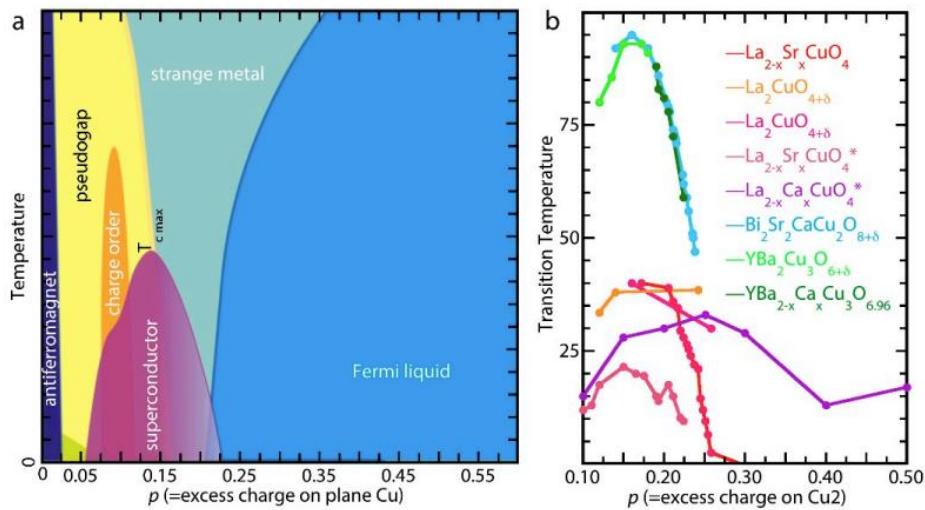
Electronic properties of complex oxides

Layered structures: cuprates

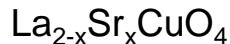


N. Barišić, PNAS 2013 110 (30)

High T_c superconductors



L. Sederholm, Condens. Matter 2021, 6, 50



$[\text{Sr}'_{\text{La}}] = [h^\bullet]$